

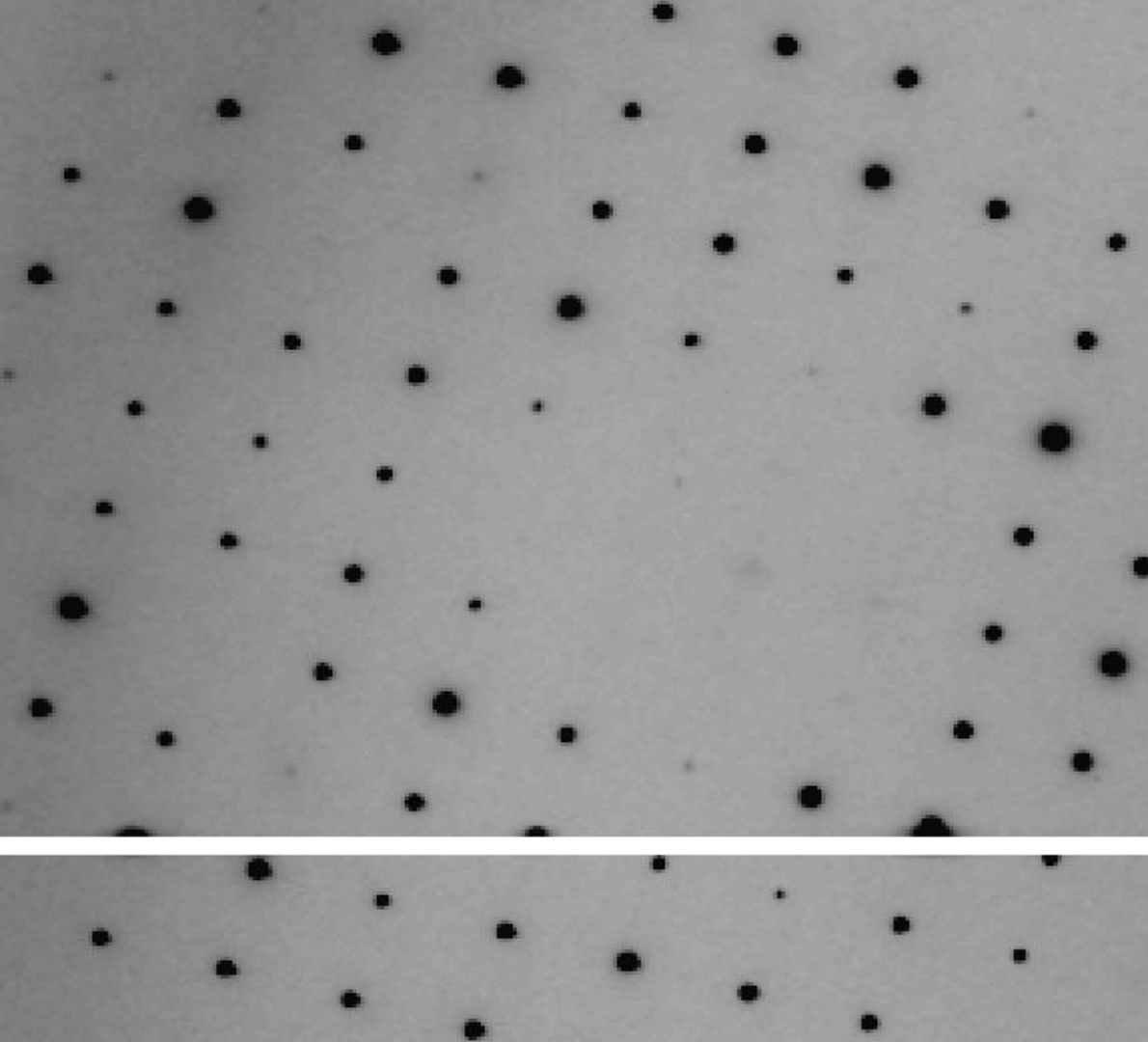
Data processing with DIALS

...

James Parkhurst

CCP4 Spring-8 workshop, January 2017

**What are we doing and why are we
doing it?**



Compute the intensity of each Bragg spot in a set of diffraction images

$$|F_{hkl}| = \sqrt{\frac{K I_{hkl}}{Lp}}$$

K = constant for given crystal

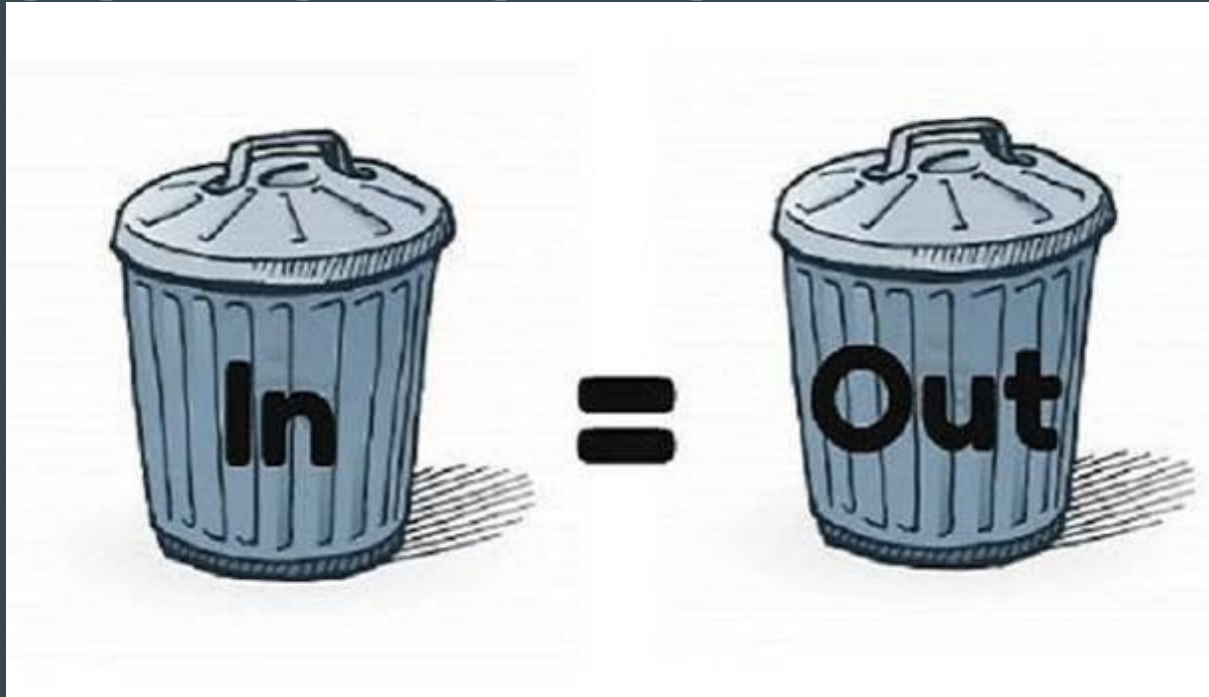
L = Lorentz factor

p = polarization factor

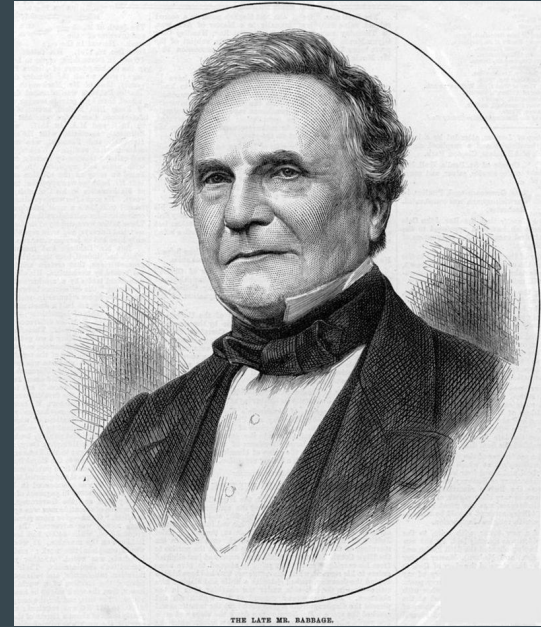
$$\rho(x, y, z) = \frac{1}{V} \sum_h \sum_k \sum_l F_{hkl} e^{-2\pi i(hx + ky + lz)}$$

Electron density at every point in the cell depends on the intensity of every reflection. We need to measure our intensities as well as possible!

Warning: garbage in, garbage out



Data collection is the last experimental stage; if you collect bad data you are stuck with it! Data processing programs won't be able to rescue you!



On two occasions I have been asked, "Pray, Mr. Babbage, if you put into the machine wrong figures, will the right answers come out?" ... I am not able rightly to apprehend the kind of confusion of ideas that could provoke such a question.

- *Charles Babbage, Passages from the Life of a Philosopher*

DIALS overview

Acknowledgements

research papers

Acta Crystallographica Section D

**Biological
Crystallography**

ISSN 0907-4449

XDS

Wolfgang Kabsch

Max-Planck-Institut für Medizinische Forschung,
Abteilung Biophysik, Jahnstrasse 29,
69120 Heidelberg, Germany

Correspondence e-mail:
wolfgang.kabsch@mpimf-heidelberg.mpg.de

The usage and control package *XDS* for 1 described in the con include automatic di range and recogniti Moreover, the limita number of correction pixel contents have t been restructured fo and completeness of measurement.

1. Functional speci

The program package developed for the re recorded on a plana monochromatic X-ra

XDS accepts a : rotation images from and multiwire area metrics and produce: of the reflections occ way. The program as positive amount of c incident beam and cr imposes no limitati directions of the rot oscillation range cov

Acta Crystallographica Section D

**Biological
Crystallography**

ISSN 0907-4449

J. W. Pilgrath

Molecular Structure Corporation, 9009 New
Trails Drive, The Woodlands, TX 77381, USA

Correspondence e-mail: jwp@msc.com

Two-dimensional position-sensit

The finer things in

X-ray diffraction images from sensitive detectors can be cha depending on whether the rotati is greater than or less than the c The expectations and consequen and thin images in terms of spa X-ray background and $I\sigma(I)$ software suite for processing (introduced, and results from d those from another popular pac

1. Introduction

Two-dimensional position-sensit for many years in X-ray diffract ular, data from crystals of mac oligonucleotides and their cor acquired with an area detector obsolete), a multi-wire system recently commercialized char coupled to a phosphor-coated fit detectors, the crystal, centered in oscillated around a single axis th $\sim 2.0^\circ$, while counts from diffrac for a specified time. At the en detector is read out and the cou two-dimensional array with each to a distinct position on the c

research papers

Acta Crystallographica Section D

**Biological
Crystallography**

ISSN 0907-4449

Andrew G. W. Leslie

MRC Laboratory of Molecular Biology,
Hills Road, Cambridge CB2 2QH, England

Correspondence e-mail:
andrew@mrc-lmb.cam.ac.uk

The integrati

The objective of any produce from a set of with their associated uncertainties), togeth crystal unit-cell param reliable, but should i intervention. The pro three stages. The first parameters may indic: The second step is to r parameters and also l known as post-refiner images, which consists reflections on each in intensity of each reflex out while simultaneou parameters. Basic fea each of these three st with reference to the |

1. Introduction

The collection of mac gone dramatic advanc advent of two-dimensi and CCDs, crystal cry monochromatic and

Centre National de la Recherche Scientifique
Université Paris-Sud

Laboratoire pour l'Utilisation du Rayonnement Electromagnétique

Proceedings

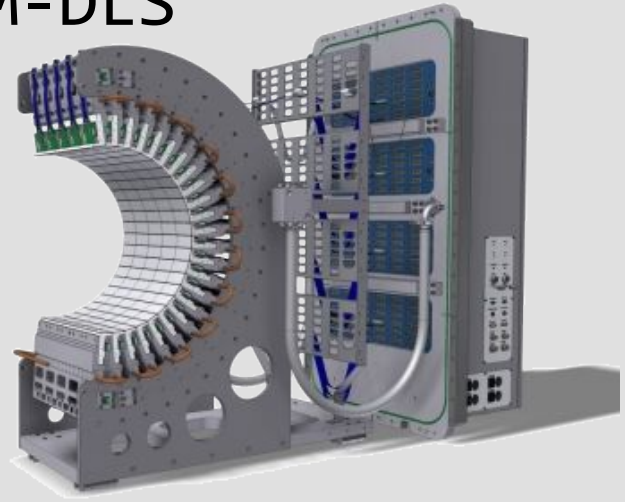
of the EEC Cooperative Workshop

on Position-Sensitive Detector Software

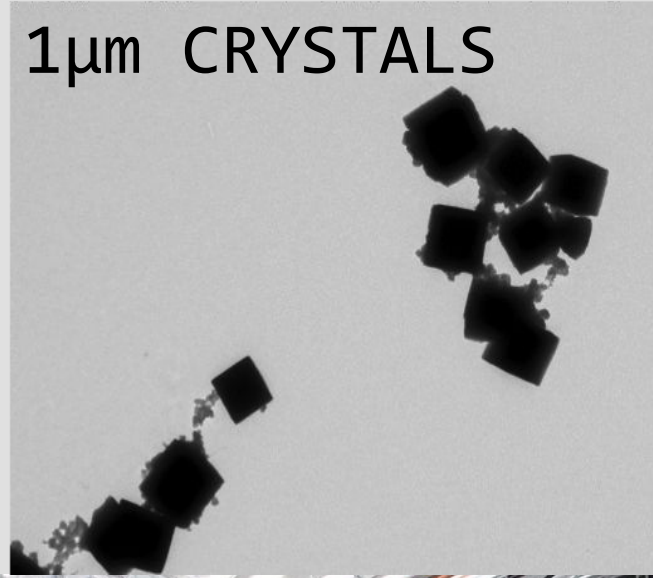
(Phases I & II)

held at L.U.R.E. from May 26 to June 7, 1986.

P12M-DLS



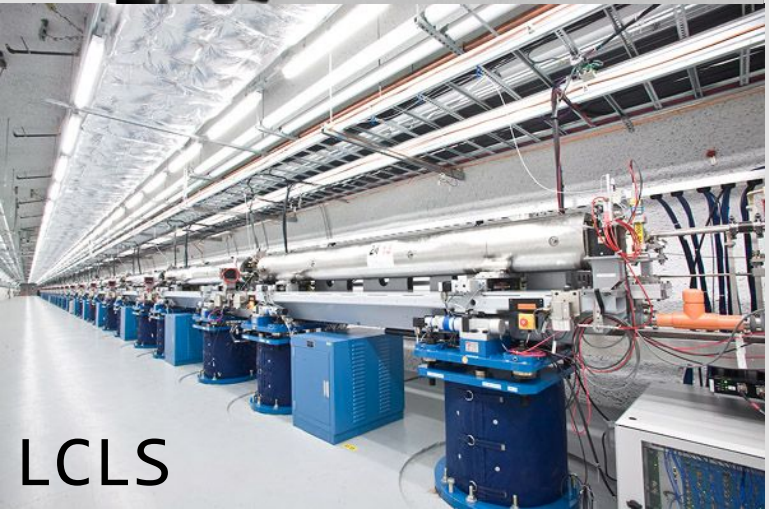
1 μ m CRYSTALS



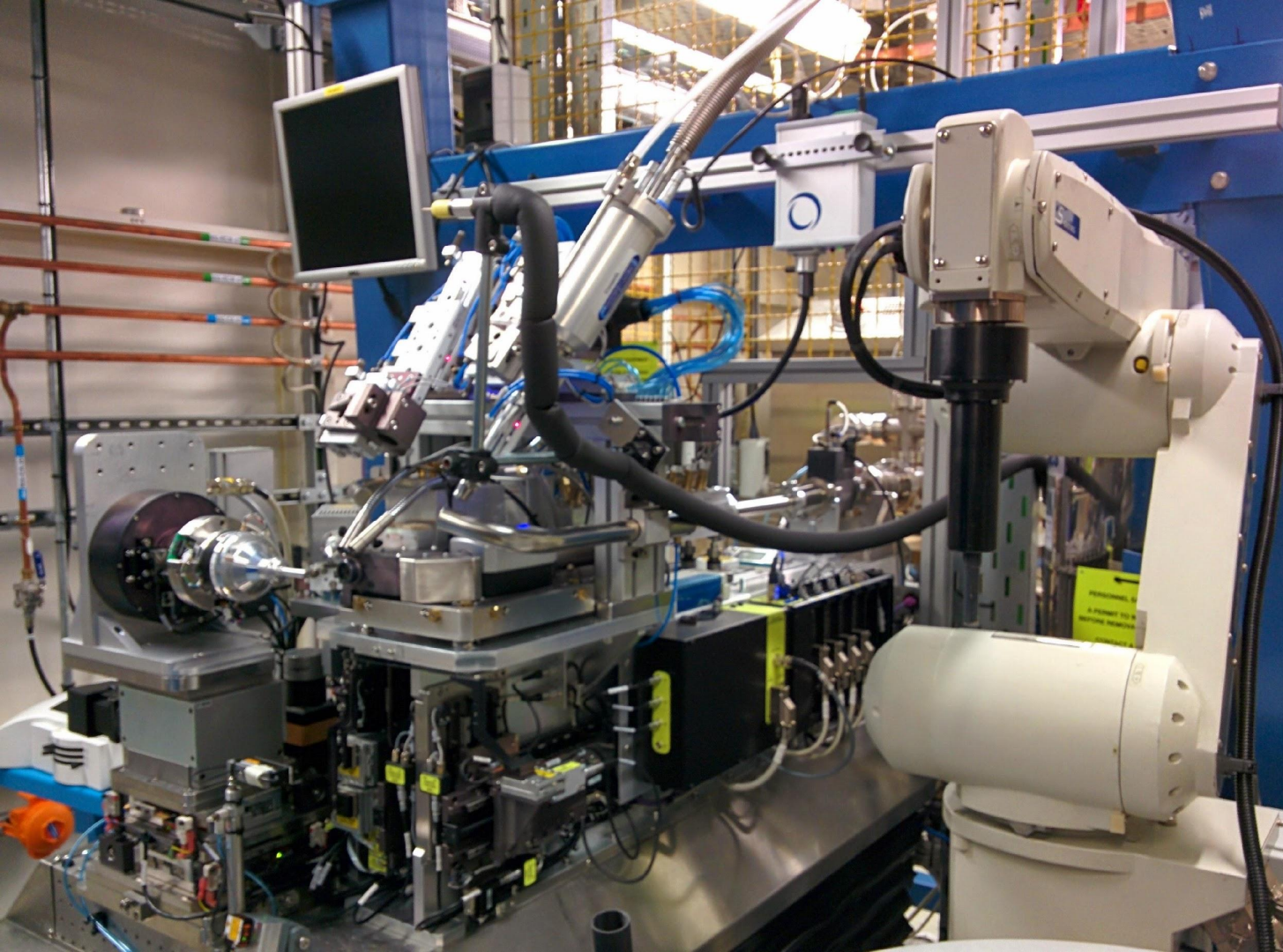
New Challenges



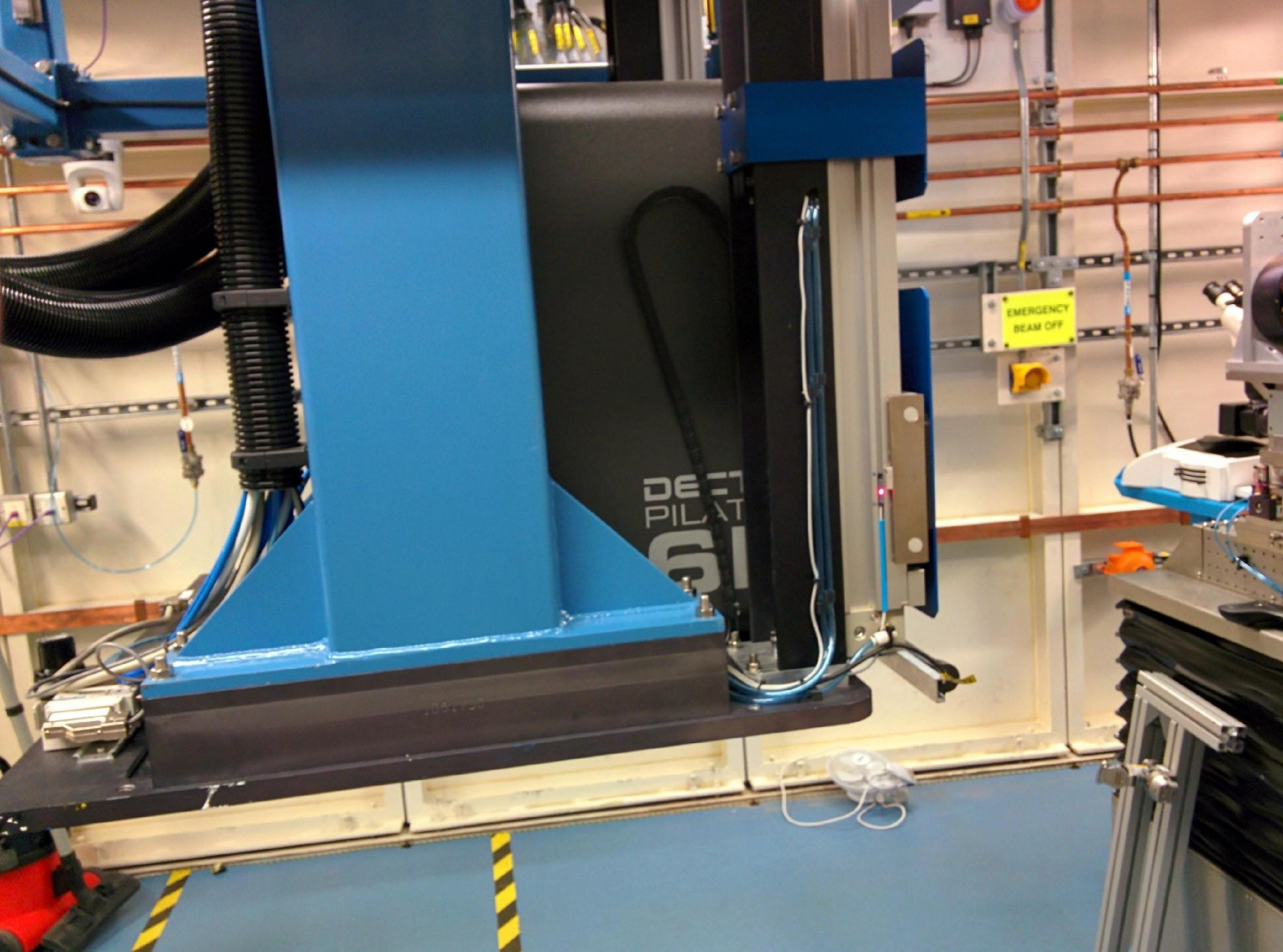
DIAMOND I24



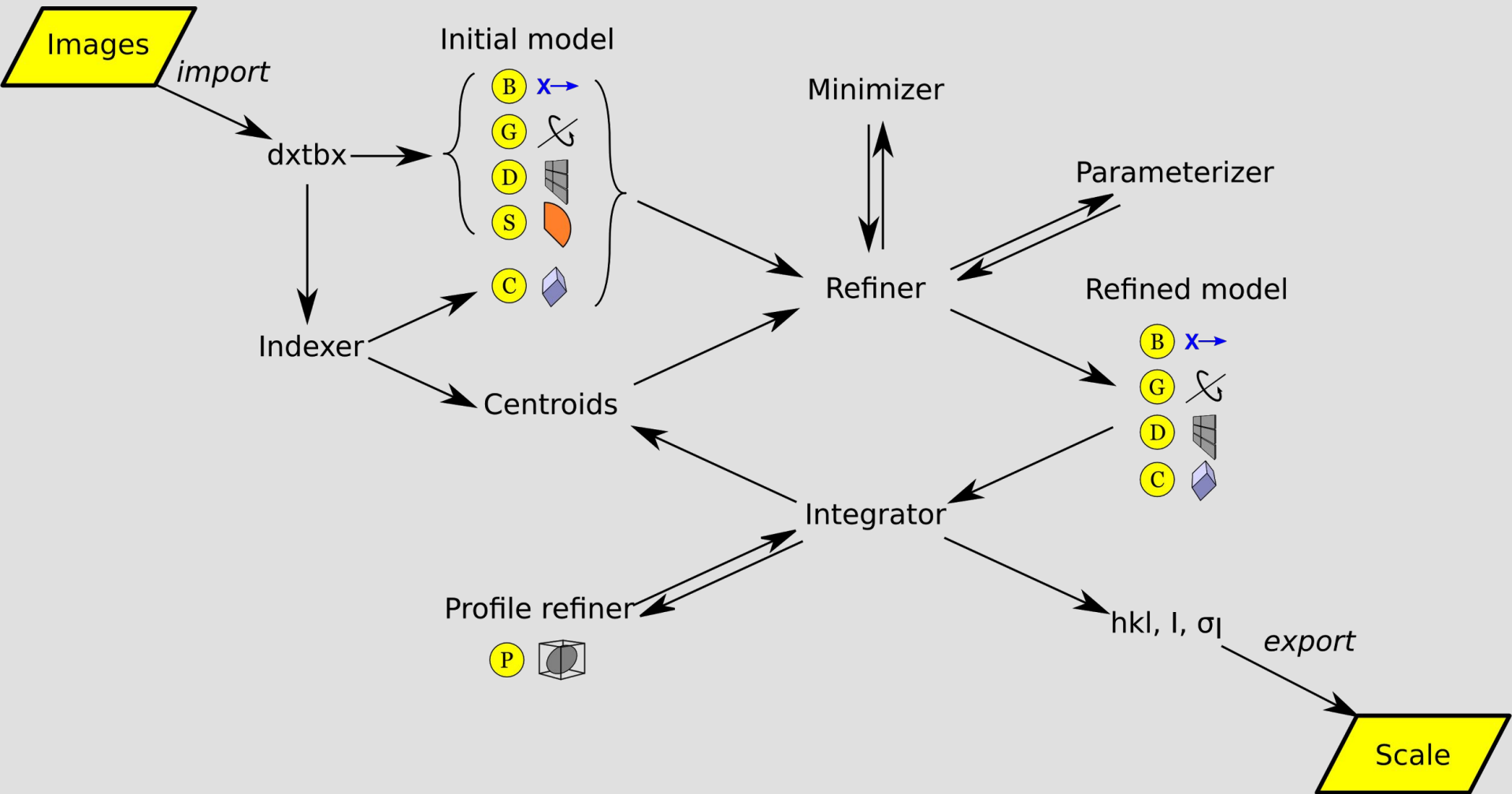
LCLS



Current
Challenges



Current Challenges



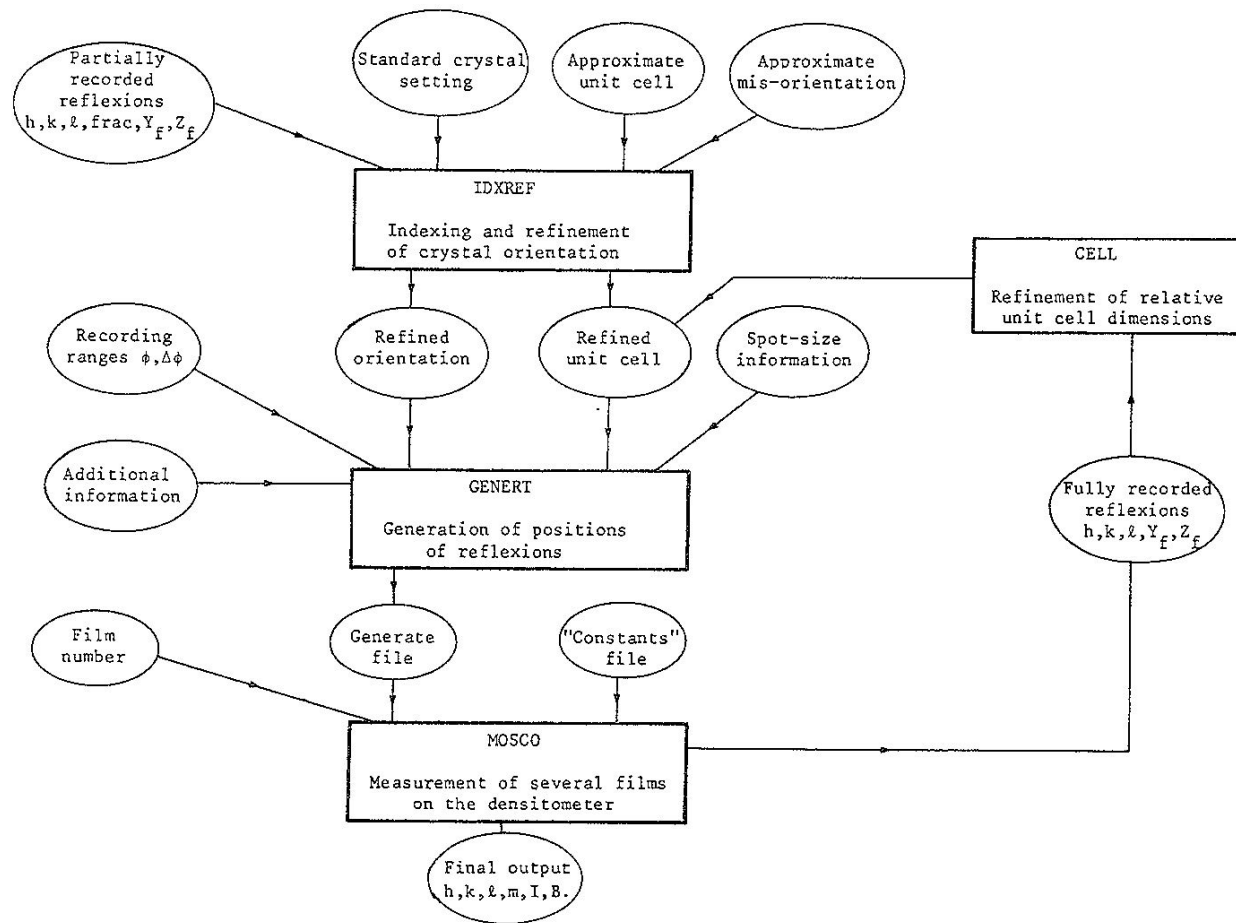


Fig. 10.1. Simplified flow-diagram of the Cambridge system, showing the inter-relation of the component programs, IDXREF, GENERT, MOSCO and CELL.

Main DIALS programs

```
dials.import  
dials.find_spots  
dials.index  
dials.refine_bravais_settings  
dials.refine  
dials.integrate  
dials.export_mtz
```

Then onwards into the CCP4 data processing pipeline:
POINTLESS → AIMLESS → CTRUNCATE...

DIALS on the command line

```
$ dials.import ${data_directory}/th_8_2_0*.cbf

$ dials.find_spots datablock.json nproc=8

$ dials.index datablock.json strong.pickle

$ dials.refine_bravais_settings experiments.json indexed.pickle

$ dials.reindex indexed.pickle change_of_basis_op=a,b,c

$ dials.refine bravais_setting_9.json reindexed_reflections.pickle outlier.algorithm=tukey
  use_all_reflections=true scan_varying=true output.experiments=refined_experiments.json

$ dials.integrate refined_experiments.json refined.pickle outlier.algorithm=null nproc=4

$ dials.export_mtz integrated.pickle refined_experiments.json hklout=integrated.mtz

$ pointless hklin integrated.mtz hklout sorted.mtz > pointless.log

$ aimless hklin sorted.mtz hklout scaled.mtz > aimless.log << eof
  resolution 1.3
  anomalous off
eof

$ ctruncate -hklin scaled.mtz -hklout truncated.mtz -colin '/*/*/[IMEAN,SIGIMEAN]' > ctruncate.log
```

Who needs a GUI?

Future: DIALS GUI (currently in development)

The screenshot displays the DIALS GUI interface. On the left is a History Tree showing a workflow: import -> find_spots -> index -> refine_bravais_settings -> reindex -> refine (highlighted) -> integrate -> export. The central area contains a toolbar with icons for home, search, pan, settings, and a plot. Below the toolbar are 'Stop' and 'Run' buttons, with the 'Run' button featuring the DIALS logo. The 'Integrate' section has two tabs: 'Simple Editor' and 'Advanced Editor'. The 'Advanced Editor' shows three parameters: 'integration.profile.fitting' set to 'True', 'integration.background.algorithm' set to 'median', and 'integration.mp.nproc' set to '1'. At the bottom left, there are four data tables: Beam, Crystal, Scan, and Detector. The right side of the interface features a 'Log View' and 'Report View' tab, an 'Img Select' dropdown, and an 'Img Palette' dropdown. Below these are two rows of image thumbnails showing diffraction patterns.

Beam	
X (mm)	Y (mm)
212.62	219.88
Wavelength (Å)	
0.98	

Crystal		
a	b	c
42.36	42.36	39.71
α	β	γ
90.0	90.0	90.0
Space Group P 4		
Orientation (deg)		
rot X	rot Y	rot Z
-82.13	6.91	-33.0

Scan	
Image Range	
1	90
oscillation	1.0
Exposure time	1.0
strong spots	31840
Indexed spots	20937
refined spots	15984
prof int spots	0
sum int spots	0

Detector	
Distance (mm)	
191.98	
Number of panels 1	
Gain	1.0
Max res (Å)	1.01
Pixel size	
X (mm)	Y (mm)
0.17	0.17

Click the Dials icon to run >> Integrate

xia2 -dials \${data_directory}

```
For AUTOMATIC/DEFAULT/NATIVE
High resolution limit          1.36    6.08    1.36
Low resolution limit          53.92   53.92   1.40
Completeness                   99.8    99.9    97.8
Multiplicity                   5.3     4.9     3.1
I/sigma                        11.7    26.8    2.2
Rmerge                          0.061   0.026   0.370
Rmeas(I)                       0.075   0.032   0.521
Rmeas(I+/-)                    0.075   0.032   0.495
Rpim(I)                        0.032   0.014   0.279
Rpim(I+/-)                     0.042   0.018   0.326
CC half                         0.999   0.998   0.818
Wilson B factor                8.913
Anomalous completeness        97.5   100.0   77.3
Anomalous multiplicity         2.6    3.1    1.8
Anomalous correlation          0.005   0.204  -0.019
Anomalous slope                0.955   0.000   0.000
Total observations             292123  3747   12262
Total unique                   55480   768    3919
Assuming spacegroup: P 41 21 2
Other likely alternatives are:
P 43 21 2
Unit cell:
57.781  57.781 149.995
90.000  90.000  90.000
```


XIA2 in CCP4 I2

Job 9: Automated integration of images with DIALS - XIA2 The job is Pending

Input Results Comments




Input data

Job title

 Use data from job as input below..


Dials distribution found in : /home/david/ccp4/ccp4-7.0/bin

Location of images

Control parameters

Pipeline to run

Heavy atom type 

Dmin

Spacegroup

XIA2 DIALS pipeline



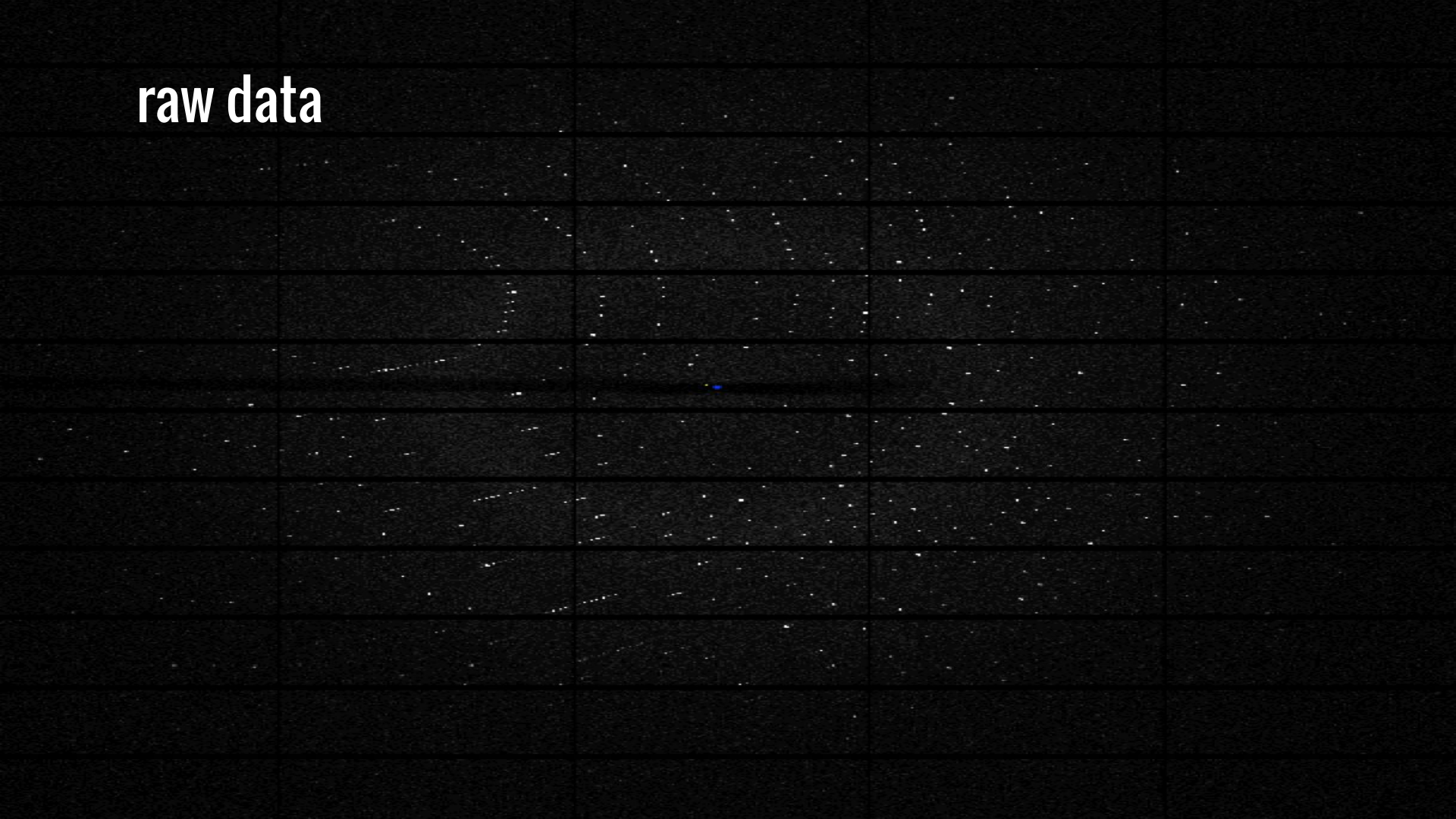
Spot finding

dials.find_spots

- Sequence of per-image filters to find strong pixels
- 3D analysis of strong pixels to identify strong spots
- Filter spots by
 - number of pixels
 - peak-centroid distance
 - resolution
 - ice rings
 - untrusted regions

```
$ dials.find_spots datablock.json nproc=8
Setting spotfinder.filter.min_spot_size=3
Configuring spot finder from Input_parameters
-----
Finding strong spots in imageset 0
-----
Finding spots in image 1 to 540...
Extracting strong pixels from images (may take a
while)
Extracted strong pixels from images
Merging 8 pixel lists
Merged 8 pixel lists with 922120 pixels
Extracting spots
Extracted 219125 spots
Calculating 219125 spot centroids
Calculated 219125 spot centroids
Calculating 219125 spot intensities
Calculated 219125 spot intensities
Found 1 possible hot spots
Found 1 possible hot pixel(s)
Filtering 219125 spots by number of pixels
Filtered 116321 spots by number of pixels
Filtering 116321 spots by peak-centroid distance
Filtered 116082 spots by peak-centroid distance
-----
Saving 116082 reflections to strong.pickle
Saved 116082 reflections to strong.pickle
Time Taken: 31.768495
```

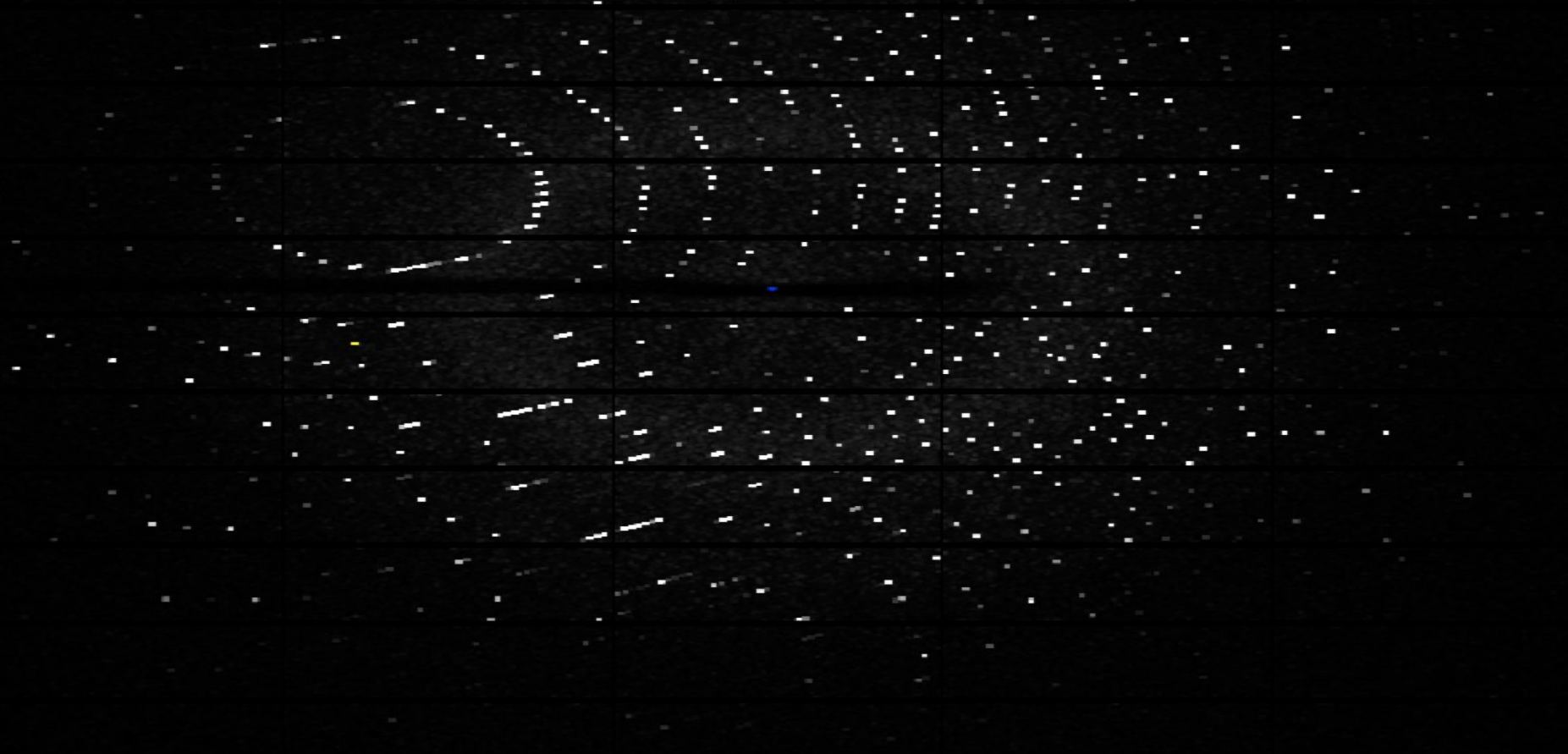
raw data



mean



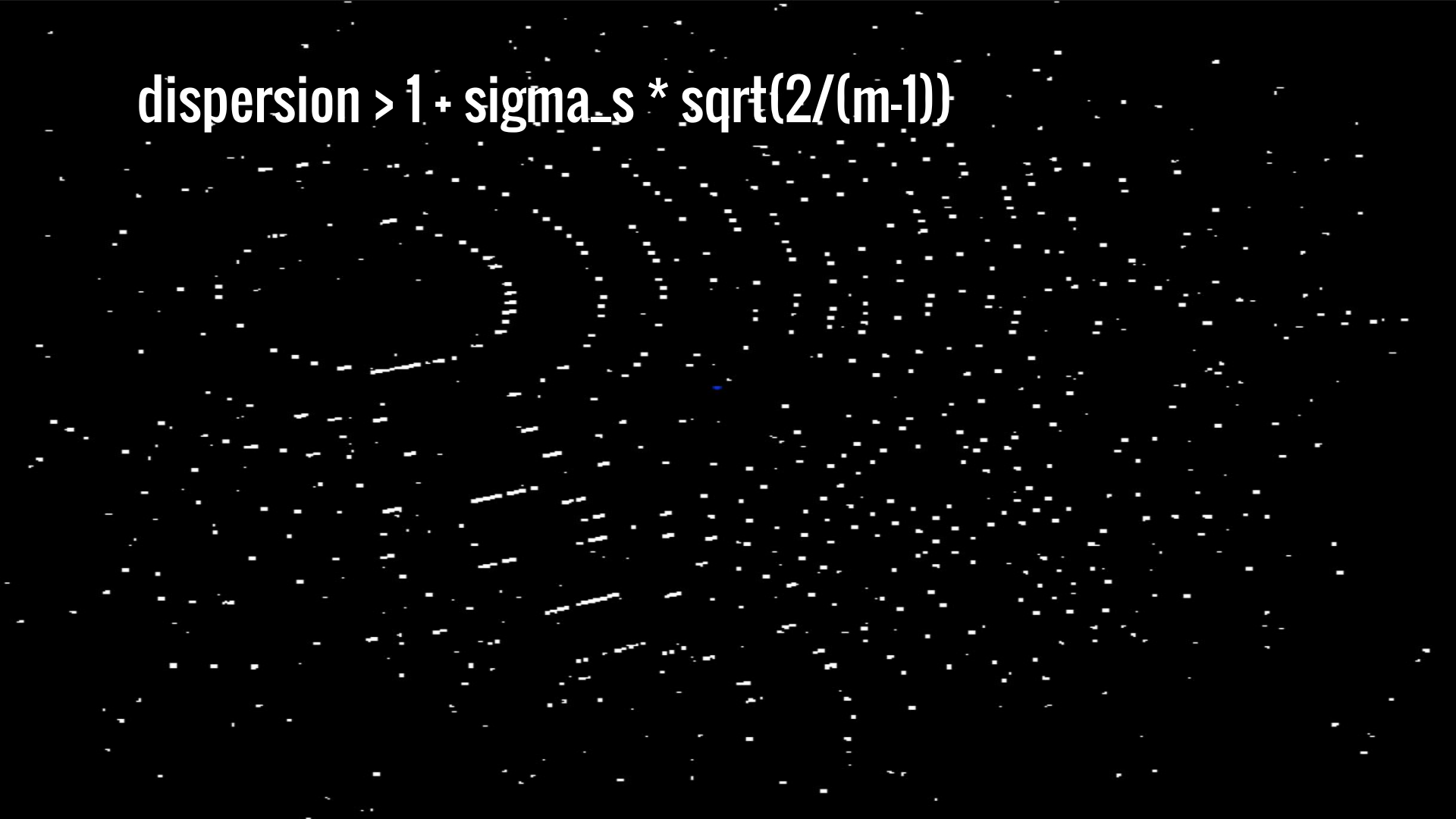
variance



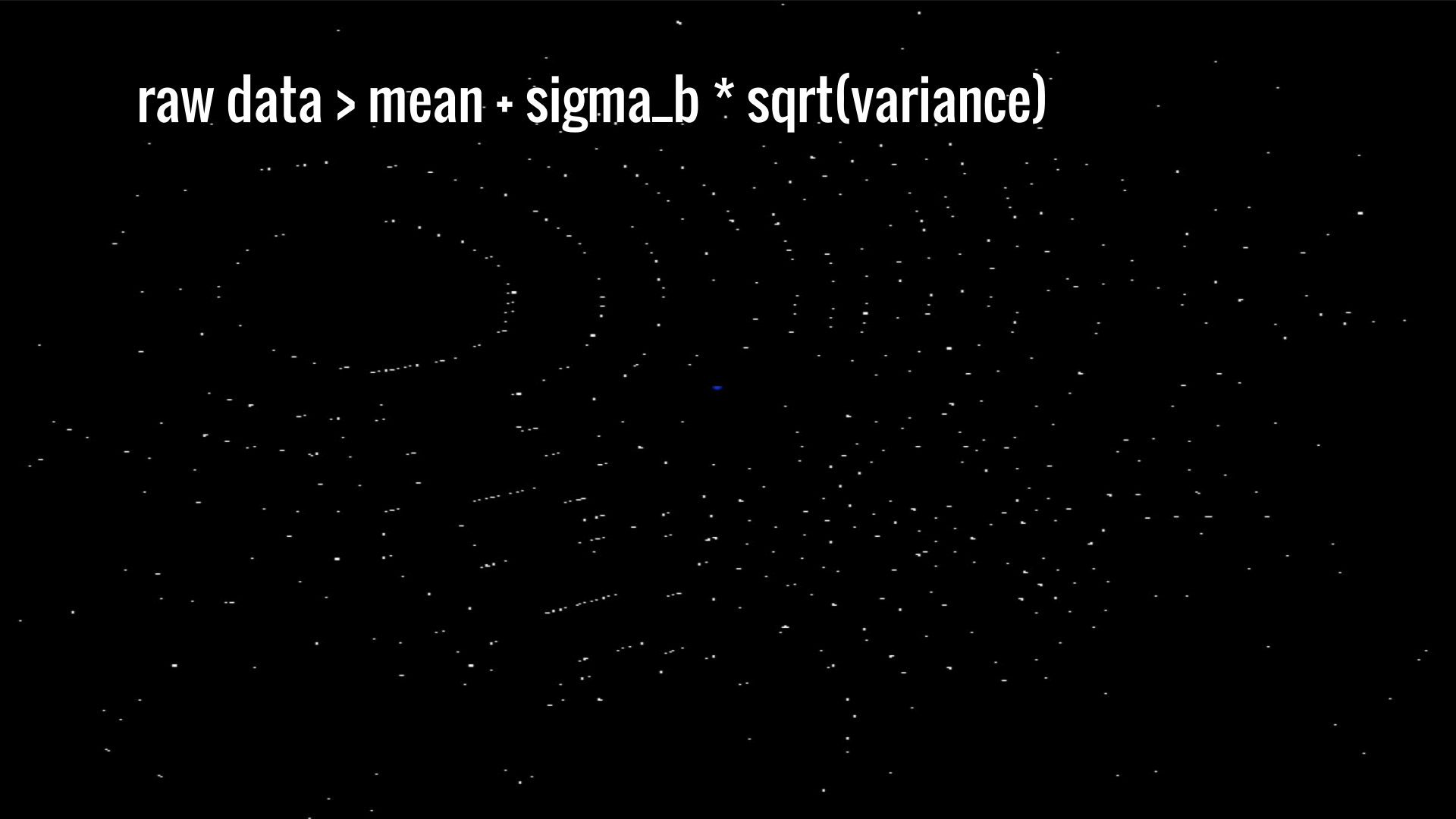
dispersion = variance / mean



$\text{dispersion} > 1 + \text{sigma}_s * \text{sqrt}(2/(m-1))$



raw data > mean + sigma_b * sqrt(variance)



./saturn/lyso_00001.img

Load file Save As... Image: lyso_00001.img [1] Previous Next Jump to image: 1

Settings

Zoom level: 100%
Color scheme: grayscale
Brightness: 100

Show resolution rings Show ice rings
 Mark beam center Mark centers of mass
 Spot max pixels Spot all pixels
 Draw reflection shoebox Show predictions
 Show hkl

Sigma background: 6.0
Sigma strong: 3.0
Global Threshold: 0.0
Min. local: 2
Gain: 1.0
Kernel size: 3 3

Default spot finding parameters are often not suitable for CCD images

./saturn/lyso_00001.img

Load file Save As... Image: lyso_00001.img [1] Previous Next Jump to image: 1

Settings

Zoom level: 100%

Color scheme: grayscale

Brightness: 100

Show resolution rings Show ice rings

Mark beam center Mark centers of mass

Spot max pixels Spot all pixels

Draw reflection shoebox Show predictions

Show hkl

Sigma background 6.0

Sigma strong 10.0

Global Threshold 0.0

Min. local 2

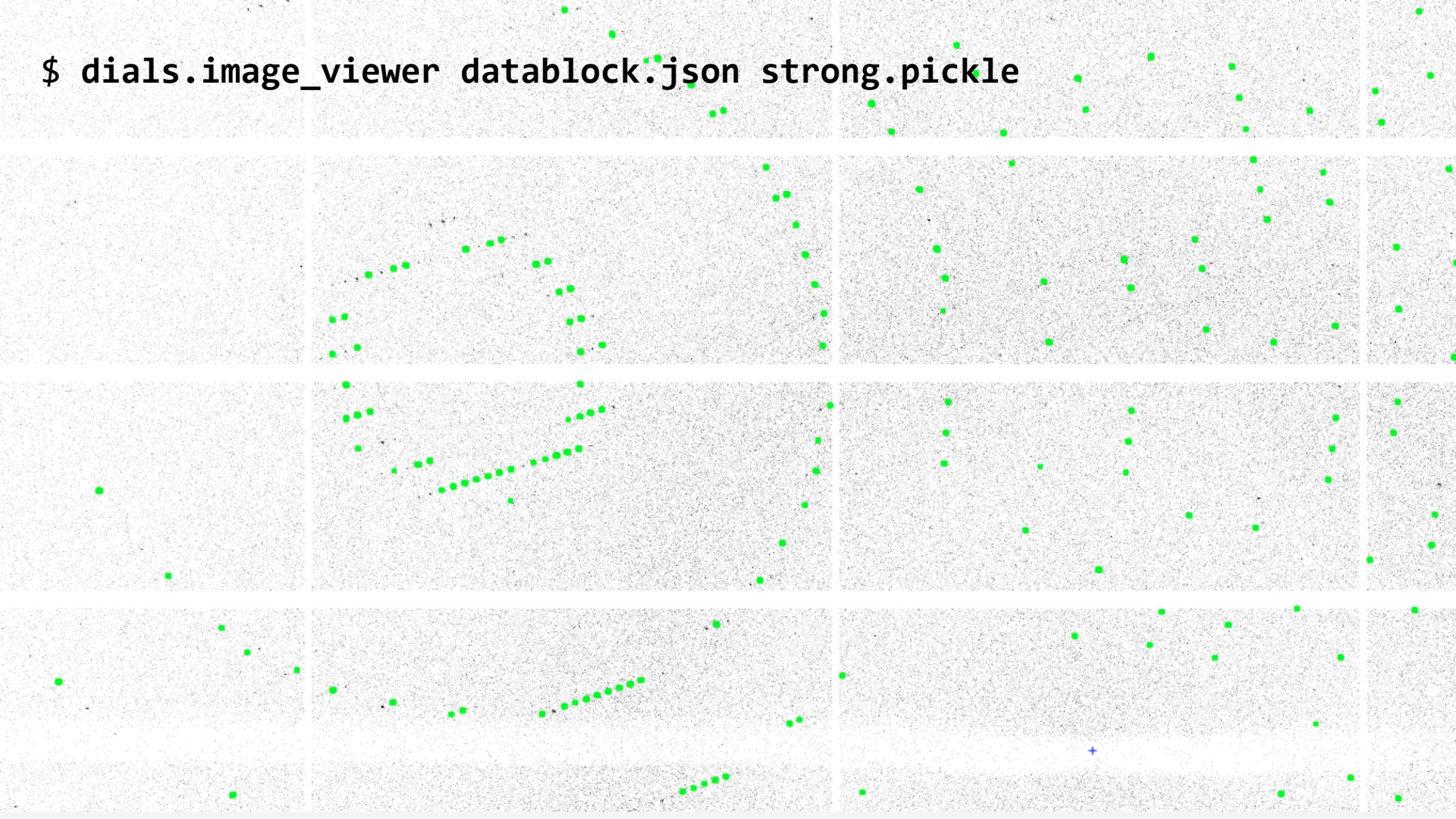
Gain 1.0

Kernel size 3 3

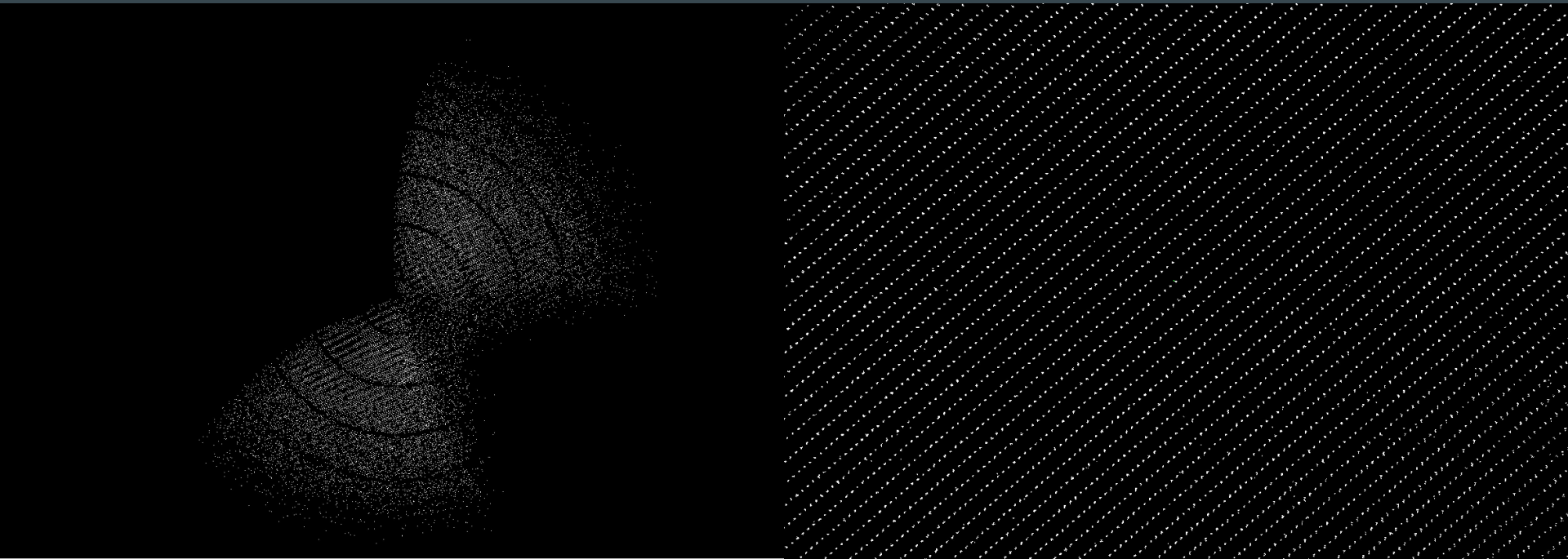
Click and drag to pan; middle-click and drag to plot intensity profile, right-click to zoom

Default spot finding parameters are often not suitable for CCD images

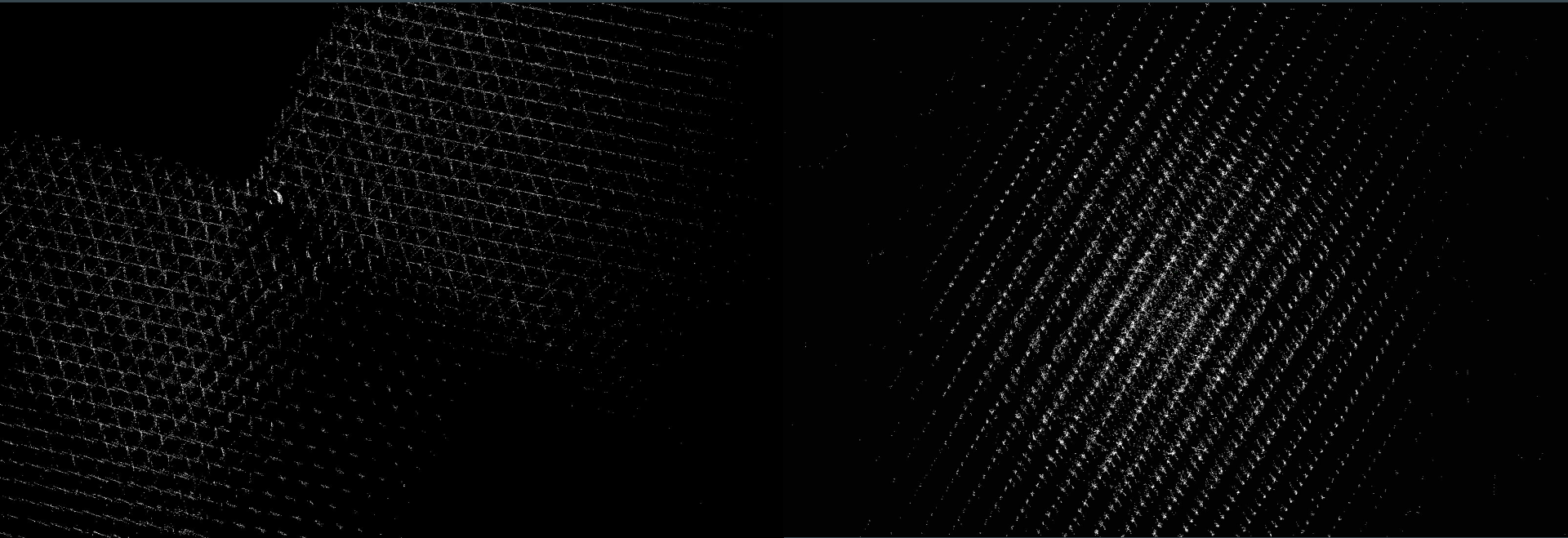
```
$ dials.image_viewer datablock.json strong.pickle
```



```
$ dials.reciprocal_lattice_viewer datablock.json strong.pickle
```

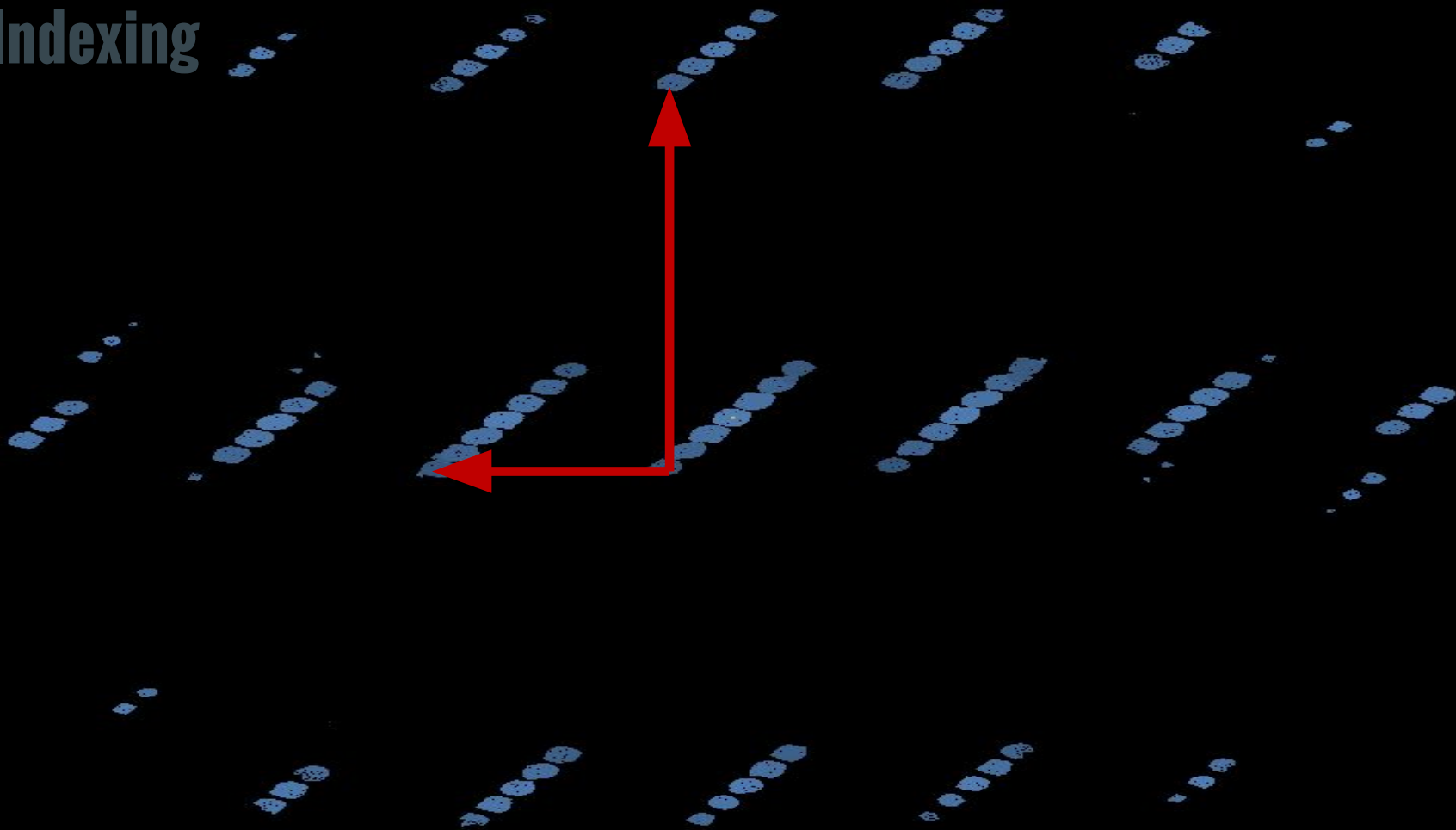


```
$ dials.reciprocal_lattice_viewer datablock.json strong.pickle
```

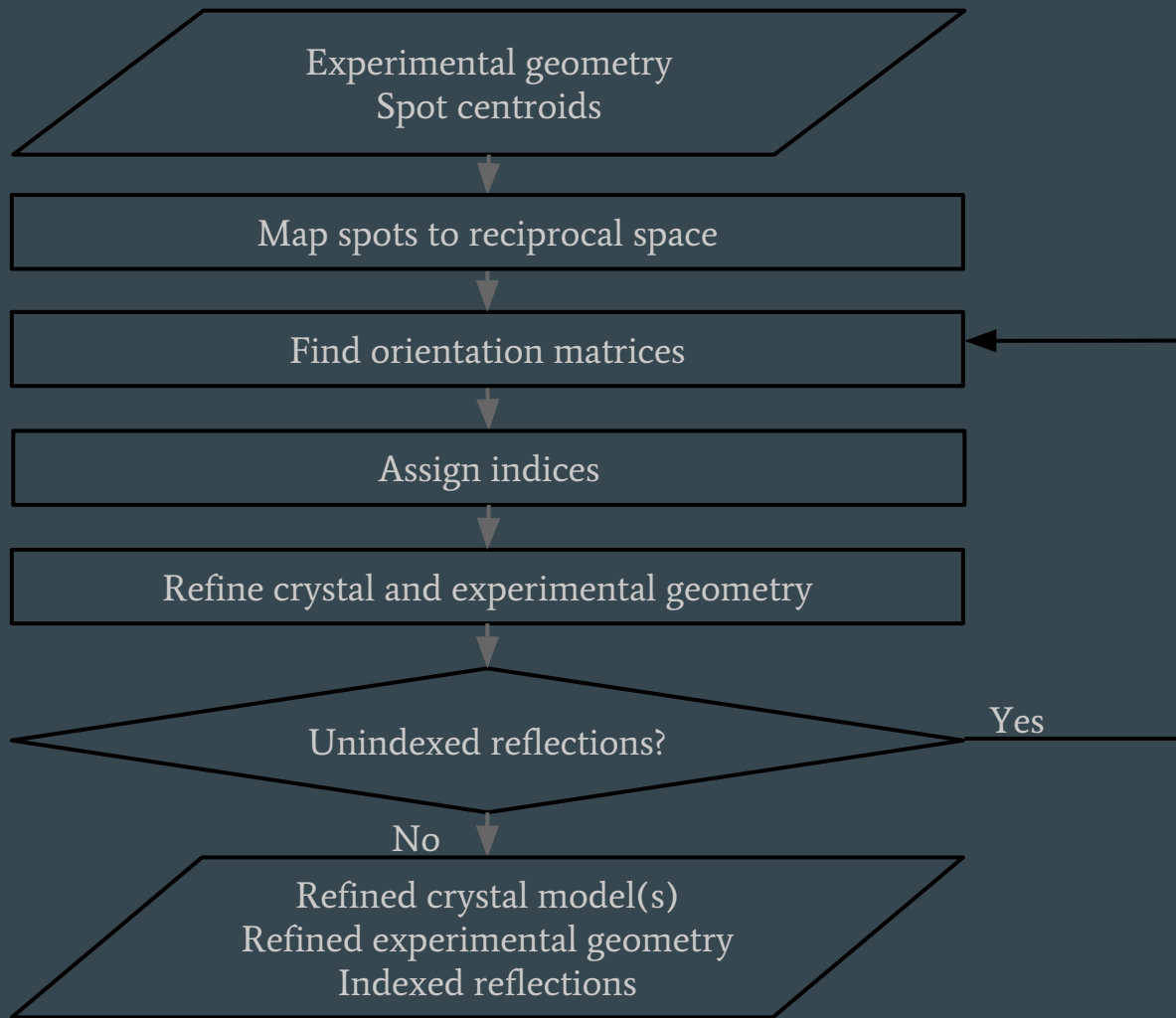


Indexing

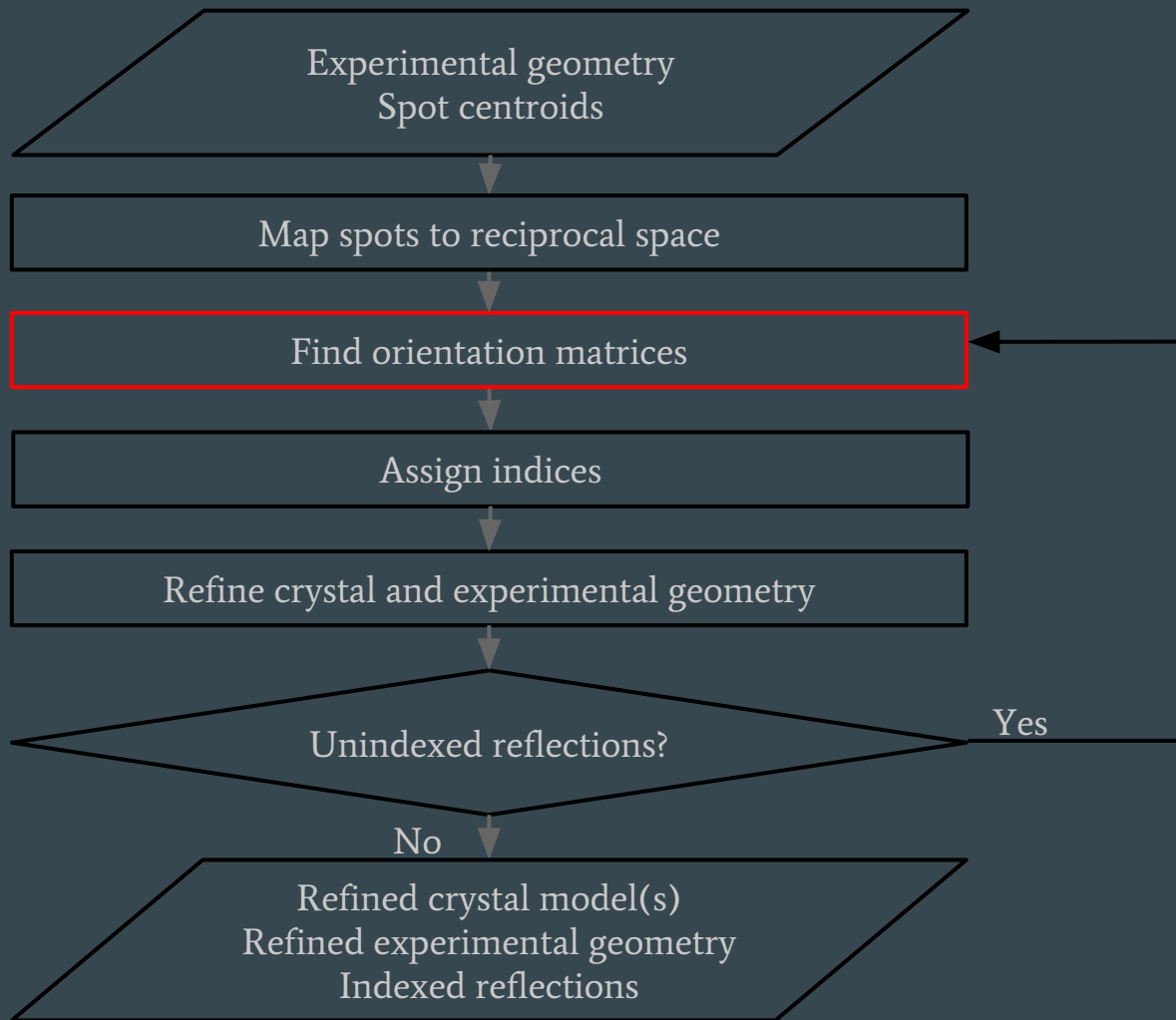
Indexing



dials.index



dials.index



dials.index

- Choice of method:
 - 1D FFT (DPS)
 - 3D FFT - **default**
 - new real space grid search algorithm
- Optionally provide known unit cell and space group

```
$ dials.index datablock.json strong.pickle
Found max_cell: 199.1 Angstrom
Setting d_min: 3.89
```

```
RMSDs by experiment:
```

Exp	Nref	RMSD_X (px) ⁻¹	RMSD_Y (px) ⁻¹	RMSD_Z (images)
0	4049	0.2881	0.25838	0.17767

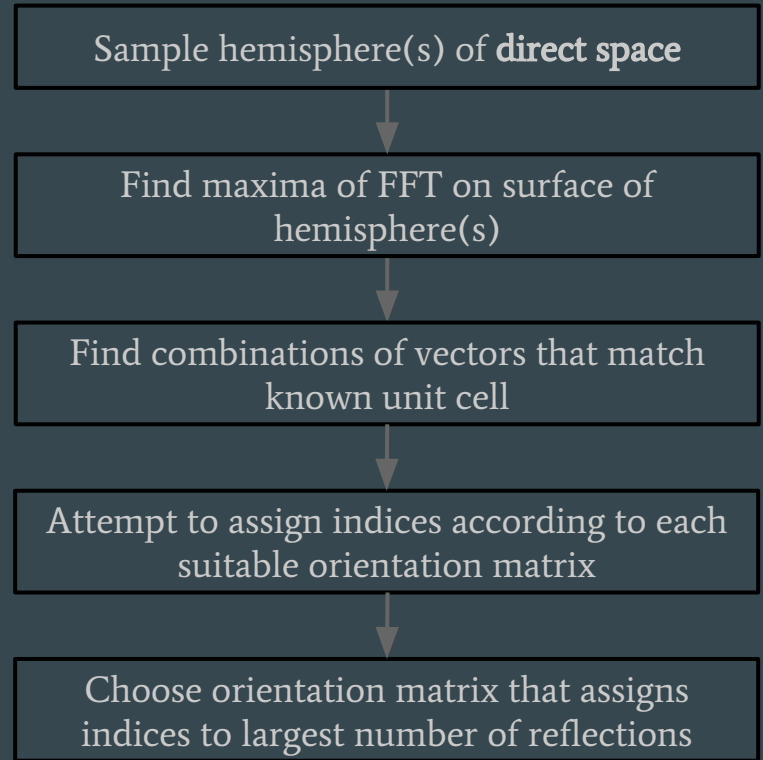
```
Final refined crystal models:
model 1 (114690 reflections):
```

```
Crystal:
  Unit cell: (57.804, 57.782, 150.027, 90.009,
             89.991, 89.990)
  Space group: P 1
  U matrix:  {{ 0.3455, -0.2589, -0.9020},
              { 0.8914,  0.3909,  0.2292},
              { 0.2933, -0.8833,  0.3659}}
  B matrix:  {{ 0.0173,  0.0000,  0.0000},
              {-0.0000,  0.0173,  0.0000},
              {-0.0000,  0.0000,  0.0067}}
  A = UB:    {{ 0.0060, -0.0045, -0.0060},
              { 0.0154,  0.0068,  0.0015},
              { 0.0051, -0.0153,  0.0024}}
```

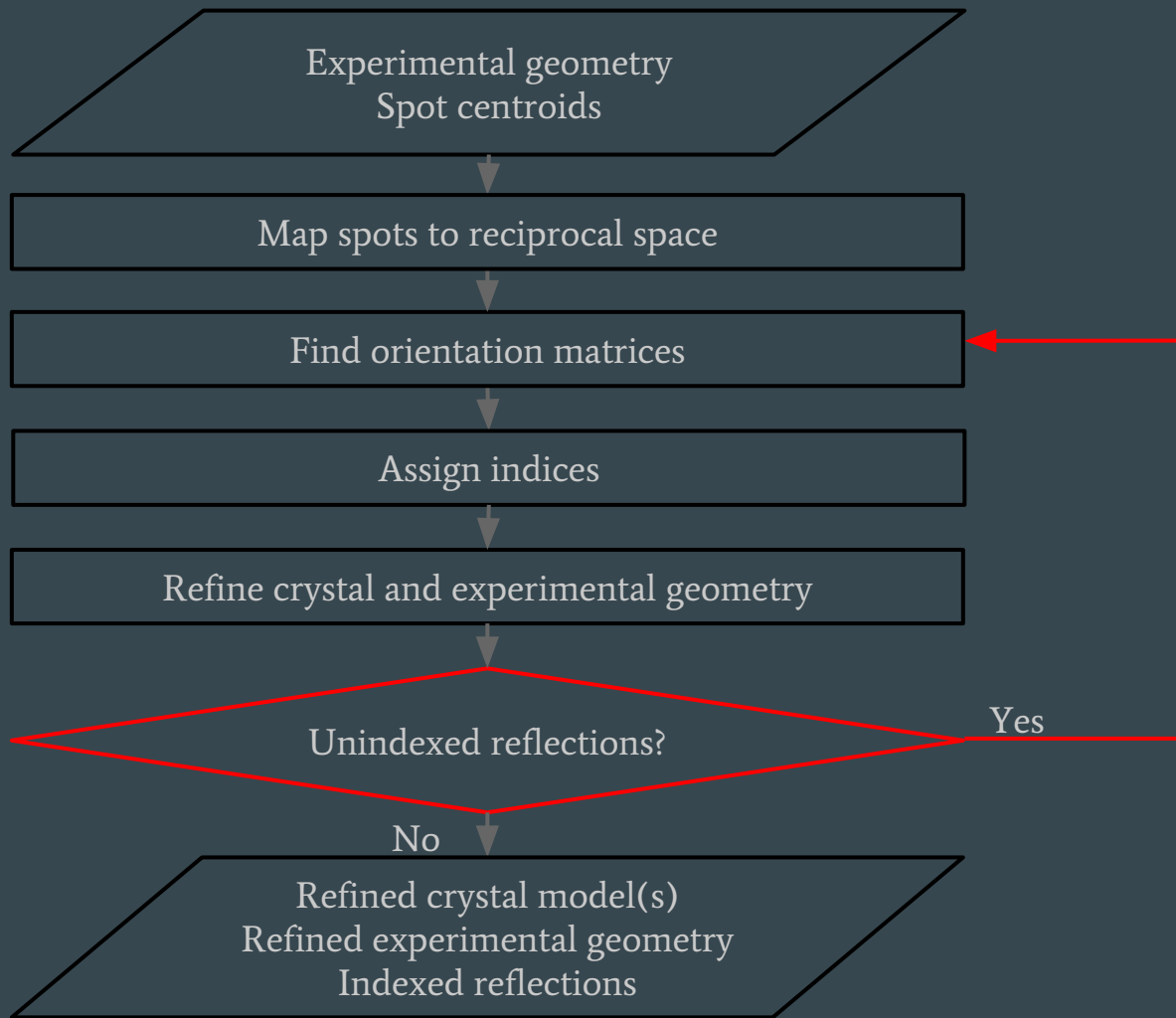
```
Saving refined experiments to experiments.json
Saving refined reflections to indexed.pickle
```

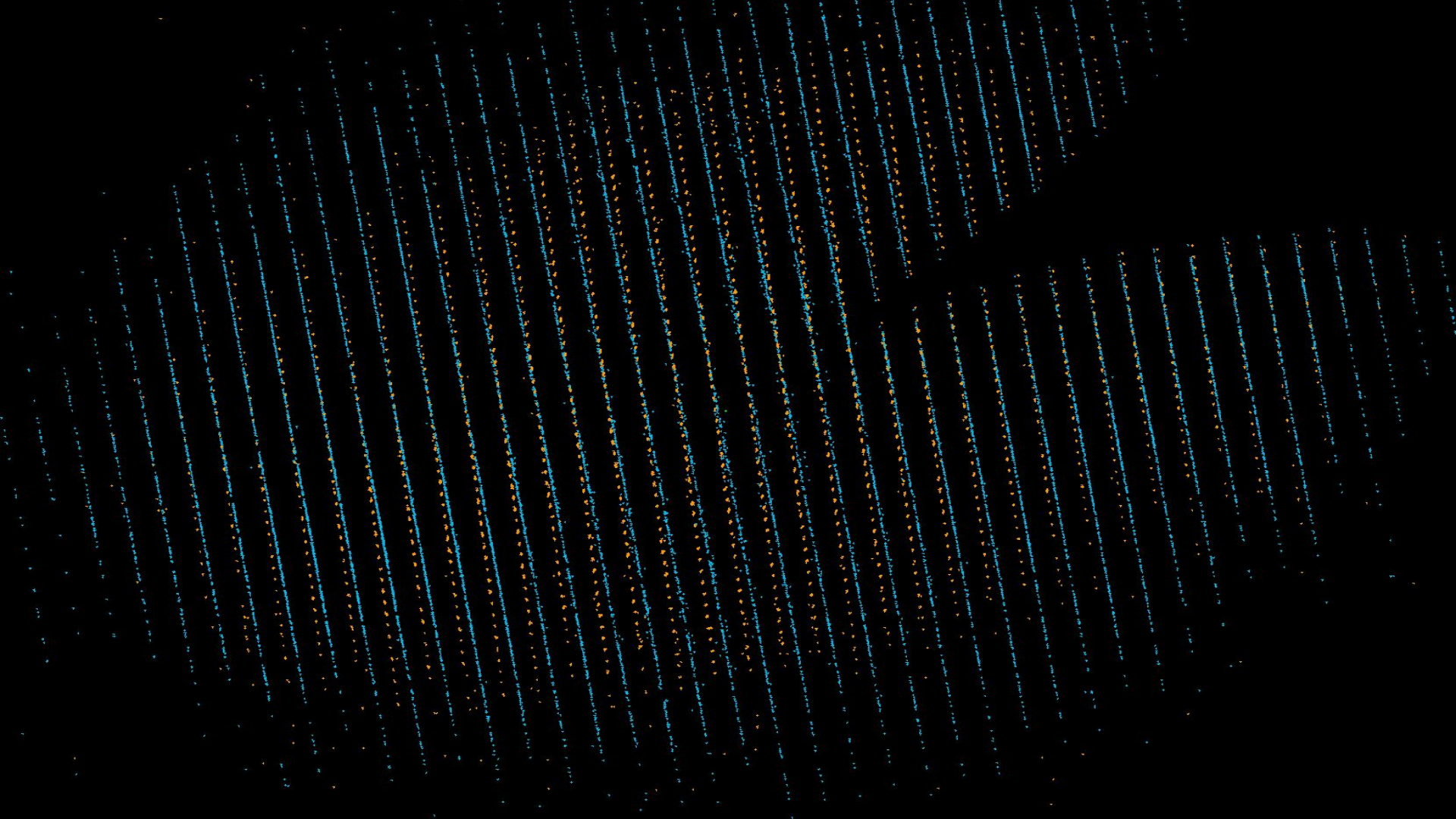
Real space grid search

- In many cases the unit cell is known - why not make use of this information?
- 1D FFT (DPS) and 3D FFT algorithms try to determine the magnitude and direction of the basis vectors simultaneously
- If the unit cell is already known, then we only need to determine the direction of the basis vectors

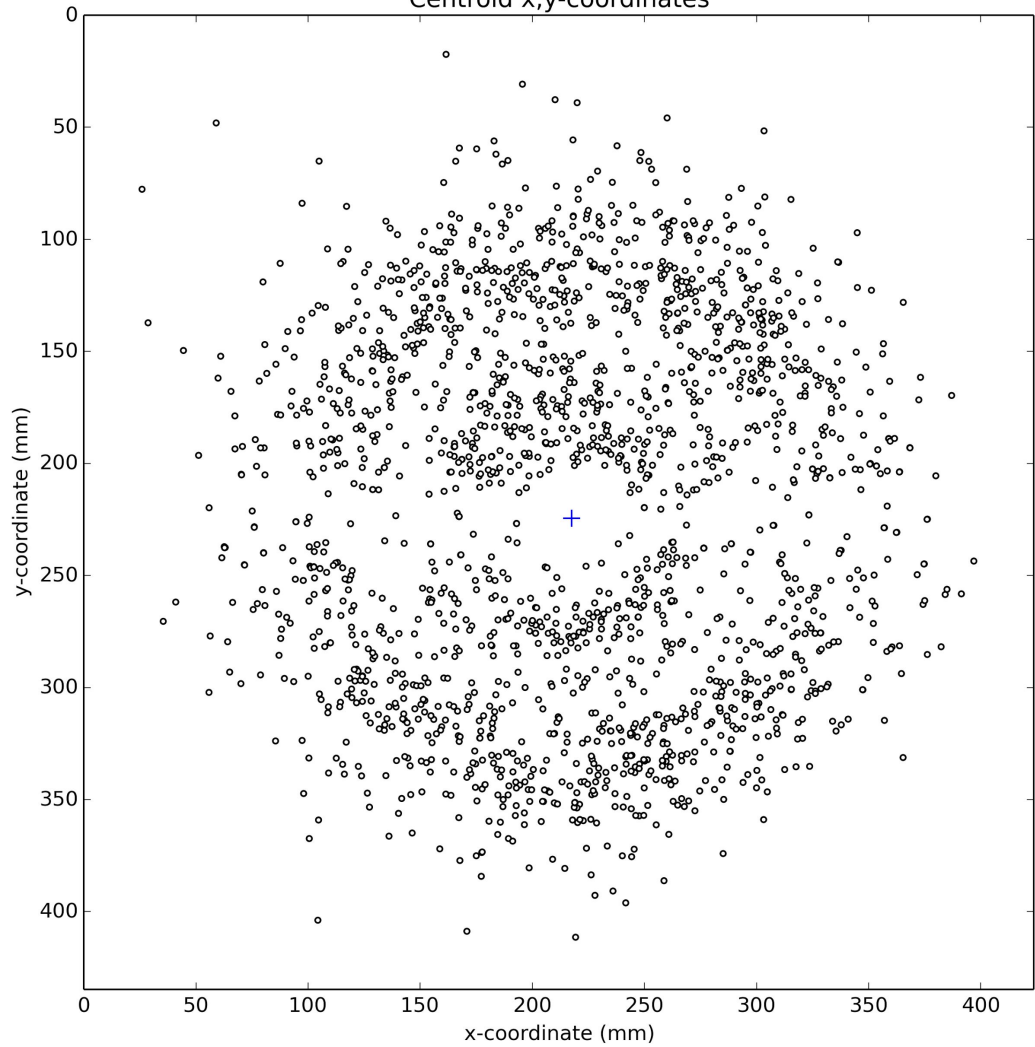


dials.index

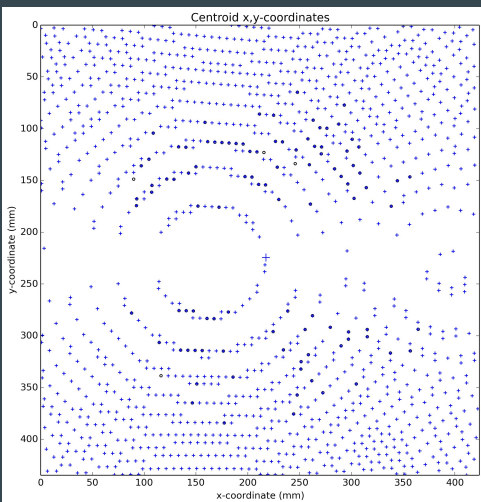
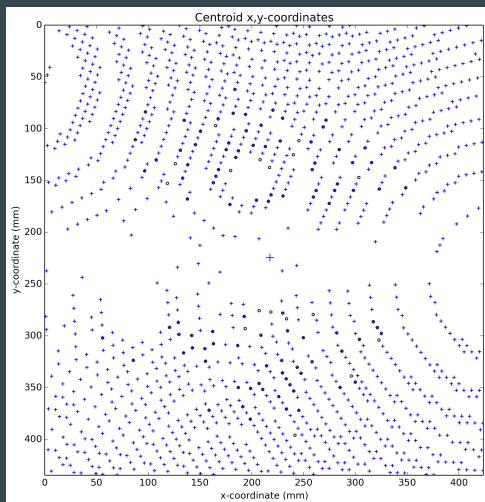
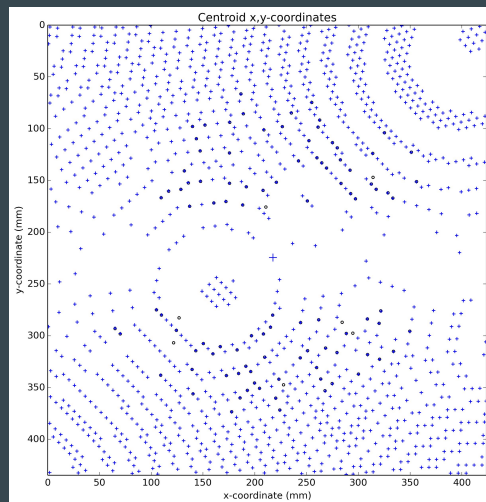
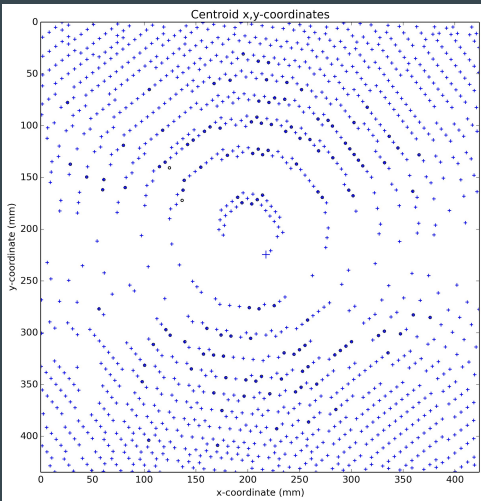
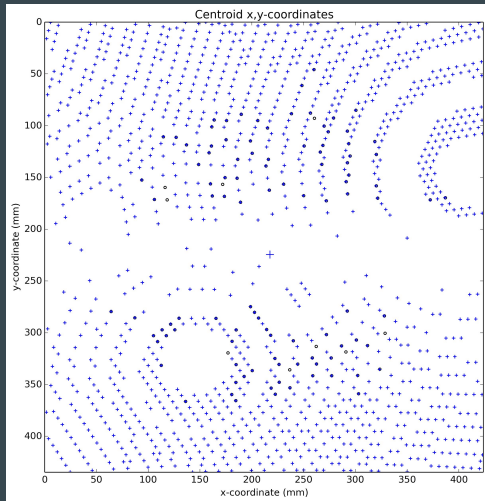
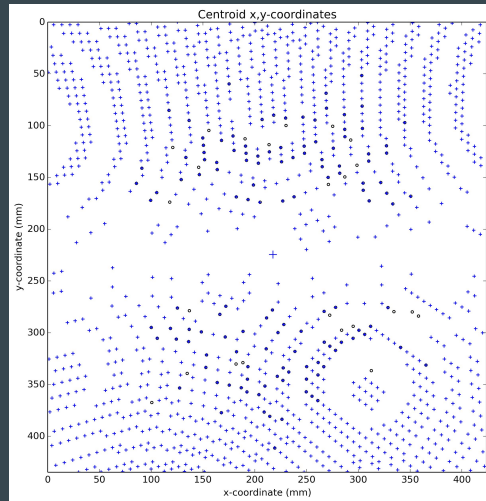




Centroid x,y-coordinates



1° wedge of data
1858 spots



6 lattices identified

dials.refine_bravais_settings

- After indexing, look for lattice symmetry
- All compatible Bravais lattices are tested
- Metric fit score, refined RMSD and symmetry element CCs are reported
- The user chooses which solution to take further

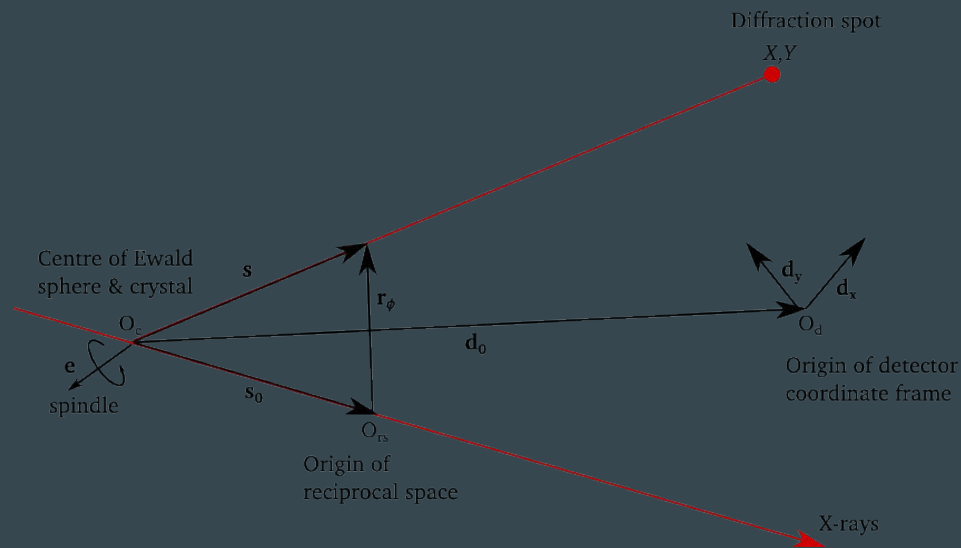
```
$ dials.refine_bravais_settings experiments.json indexed.pickle
```

```
-----  
Solution Metric fit  rmsd  min/max cc #spots lattice                unit_cell  volume  cb_op  
-----  
*  9  0.0311 0.063 0.800/0.857  8099  tP  57.78  57.78 150.00  90.00  90.00  90.00  500867  a,b,c  
*  8  0.0311 0.063 0.800/0.969  8099  oC  81.72  81.73 150.01  90.00  90.00  90.00 1002008  a-b,a+b,c  
*  7  0.0272 0.061 0.969/0.969  8099  mC  81.73  81.74 150.03  90.00  89.99  90.00 1002365  a-b,a+b,c  
*  6  0.0311 0.062 0.805/0.805  8099  mC  81.73  81.72 150.02  90.00  89.99  90.00 1002012  a+b,-a+b,c  
*  5  0.0154 0.061 0.800/0.906  8099  oP  57.79  57.76 149.99  90.00  90.00  90.00  500672  a,b,c  
*  4  0.0147 0.060 0.821/0.821  8099  mP  57.77  57.80 150.01  90.00  90.02  90.00  500853  -b,-a,-c  
*  3  0.0154 0.060 0.906/0.906  8099  mP  57.80  57.78 150.02  90.00  89.98  90.00  500945  a,b,c  
*  2  0.0152 0.061 0.800/0.800  8099  mP  57.78 150.01  57.80  90.00  89.99  90.00  500925  b,c,a  
*  1  0.0000 0.060          -/-  8099  aP  57.80  57.78 150.03  90.01  89.99  89.99  501086  a,b,c  
-----
```

```
* = recommended solution
```

Refinement

Centroid refinement



$$\mathbf{d} = (d_x | d_y | d_0)$$

$$\mathbf{D} = \mathbf{d}^{-1}$$

$$\mathbf{v} = \mathbf{D}\mathbf{s} = \begin{pmatrix} \alpha X \\ \alpha Y \\ 1/\alpha \end{pmatrix}$$

- Refine parameters that affect central impacts*
- Parameters that affect general impacts (mosaicity, $\Delta\lambda$, etc) are determined by profile modelling

*cf. EVAL package: *J. Appl. Cryst.* **36**, (2003) 220-229

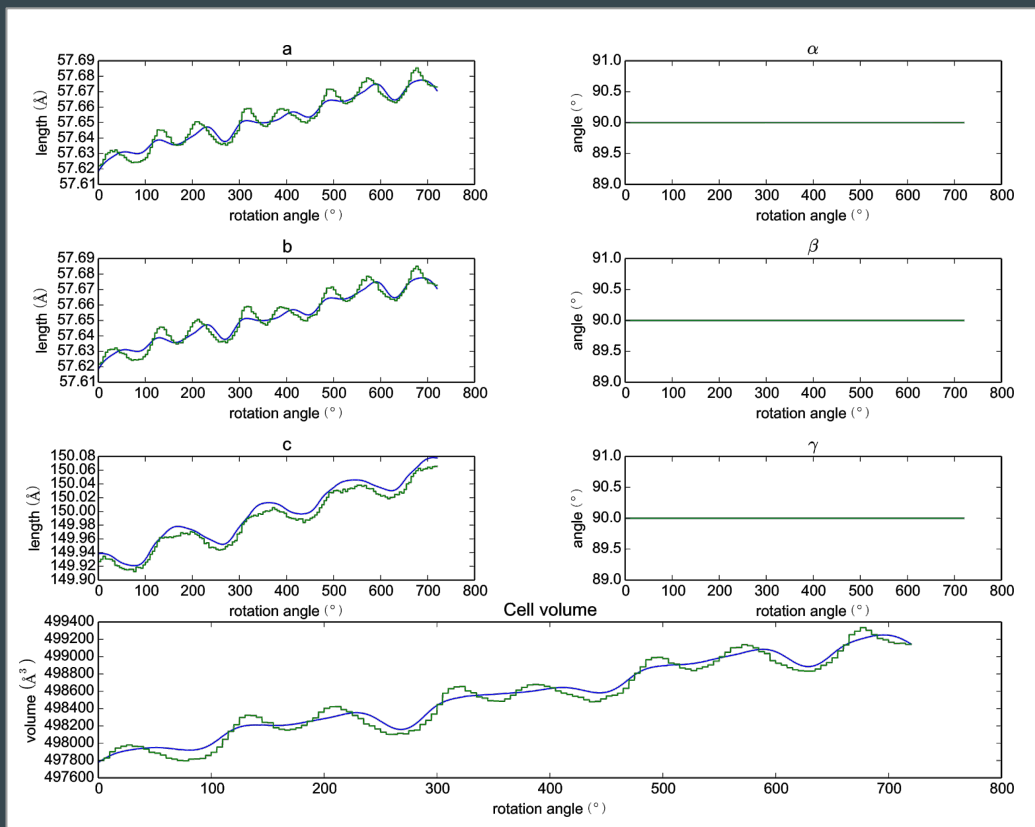
Scan-varying refinement

- We do global, not local, refinement
- How to model changes to the crystal model over time?
- Scan divided into equal-sized intervals
- Crystal parameterisation split over sample points
- Gaussian smoother, inspired by AIMLESS

Scan-varying refinement

117 parameters:

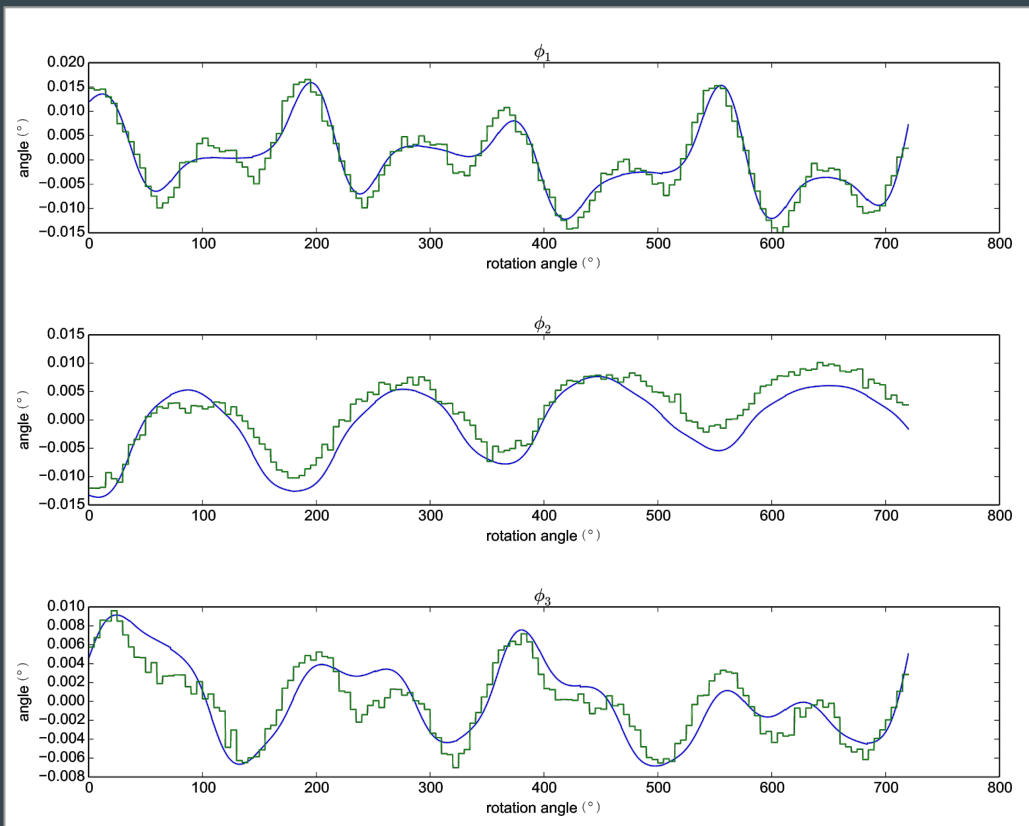
- 6 detector
- 1 beam
- 3 crystal orientation \times
22 "samples"
- 2 unit cell parameters \times
22 "samples"



Scan-varying refinement

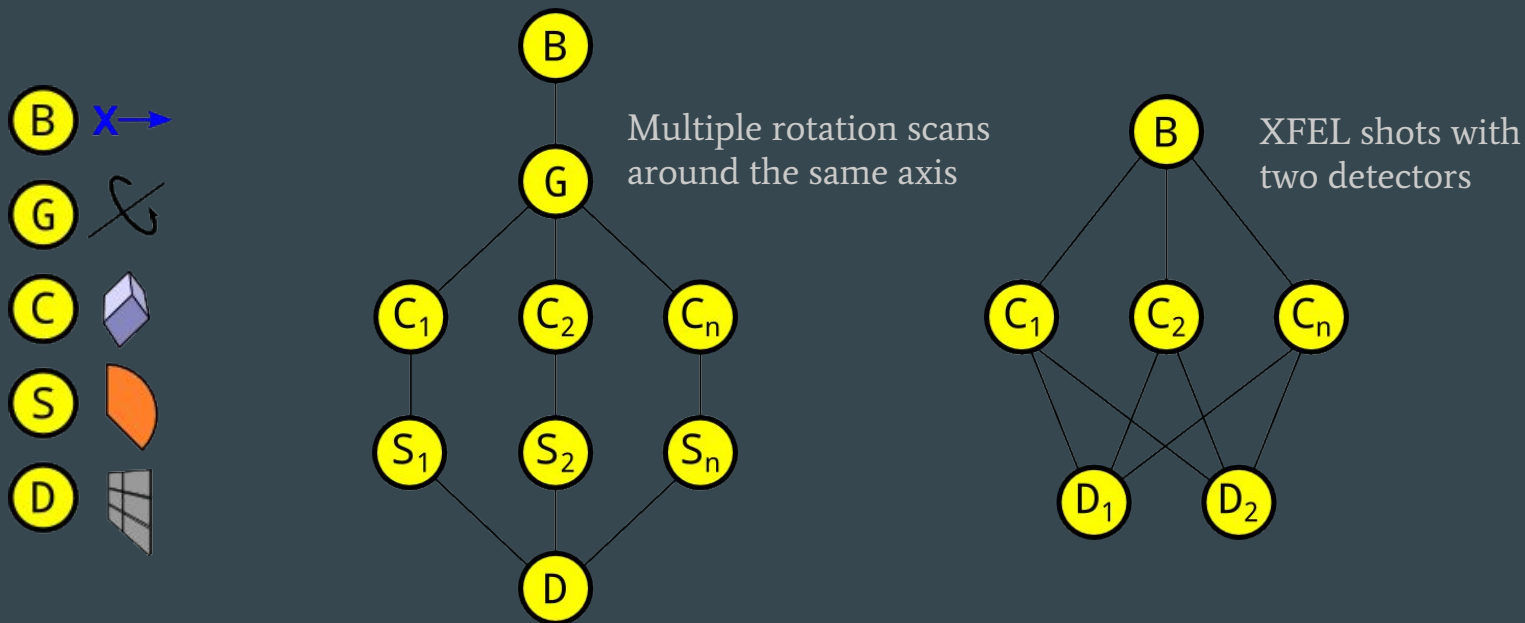
117 parameters:

- 6 detector
- 1 beam
- 3 crystal orientation \times 22 "samples"
- 2 unit cell parameters \times 22 "samples"



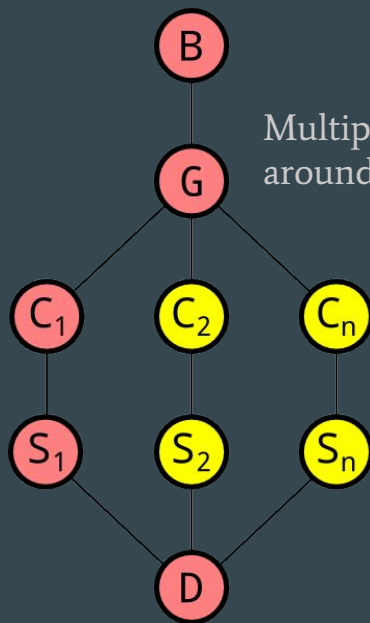
Multiple experiments

- Global refinement across datasets that share some models
- Typical use cases involve multiple crystals

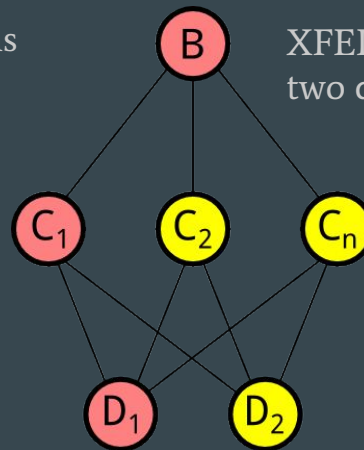


Multiple experiments

- Global refinement across datasets that share some models
- Typical use cases involve multiple crystals



Multiple rotation scans
around the same axis

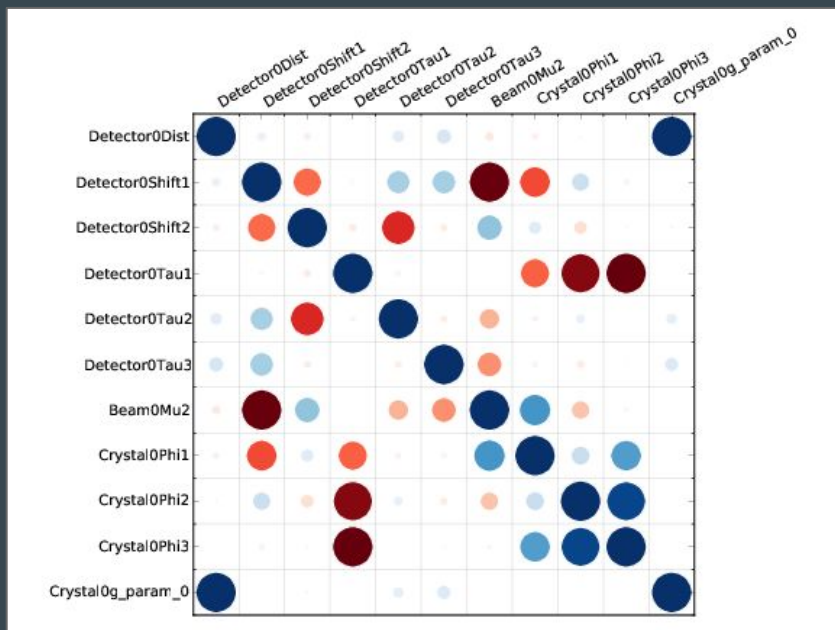


XFEL shots with
two detectors

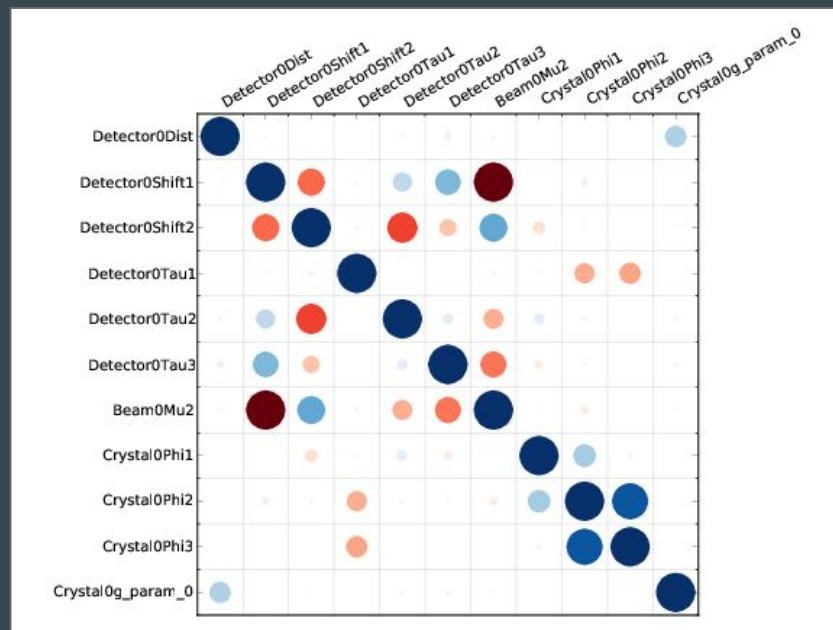
Multiple experiments

Cubic polyhedrin crystals, 1° scans

One lattice



5 sweeps (16 lattices)

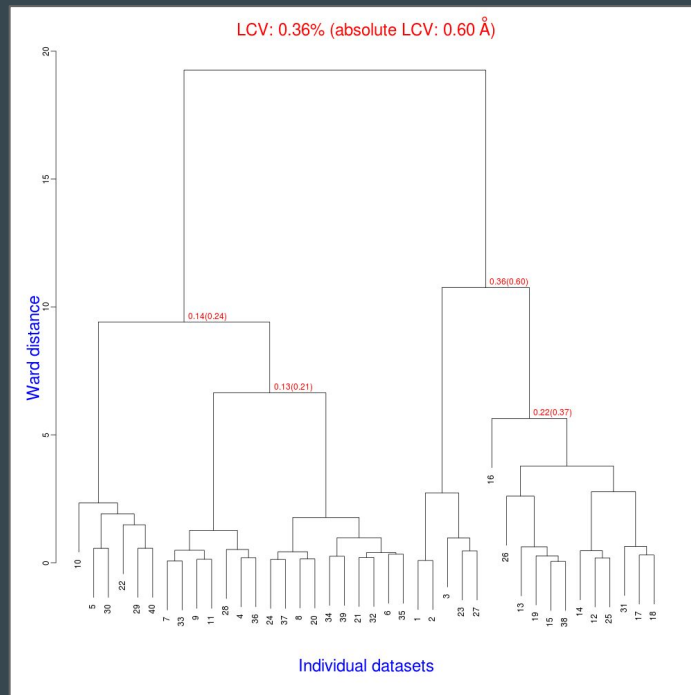
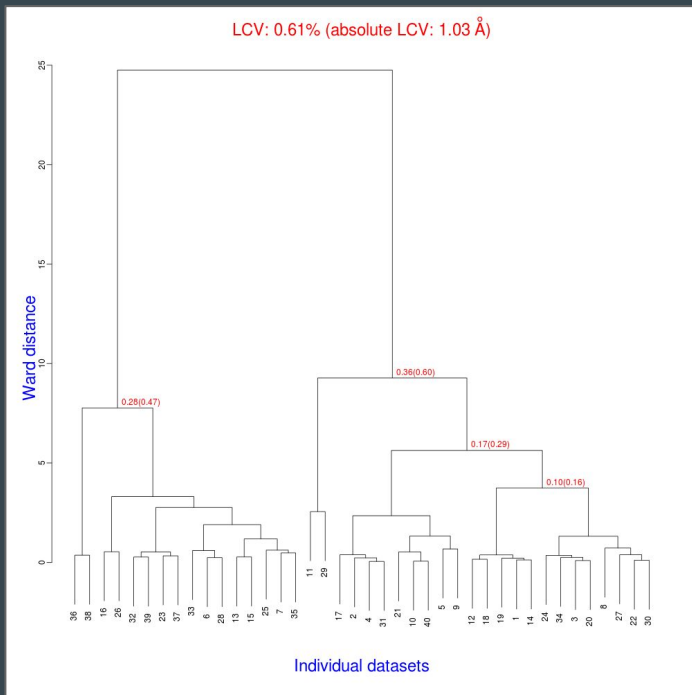


Joint refinement



Multiple experiments

Use joint refinement as a preparatory step for BLEND



TehA data. See *Acta Cryst. D* 71 (June 2015) for original analysis

Integration

Tasks in dials.integrate

Calculate the bounding box parameters from strong reflections



Predict the positions of reflections on the images

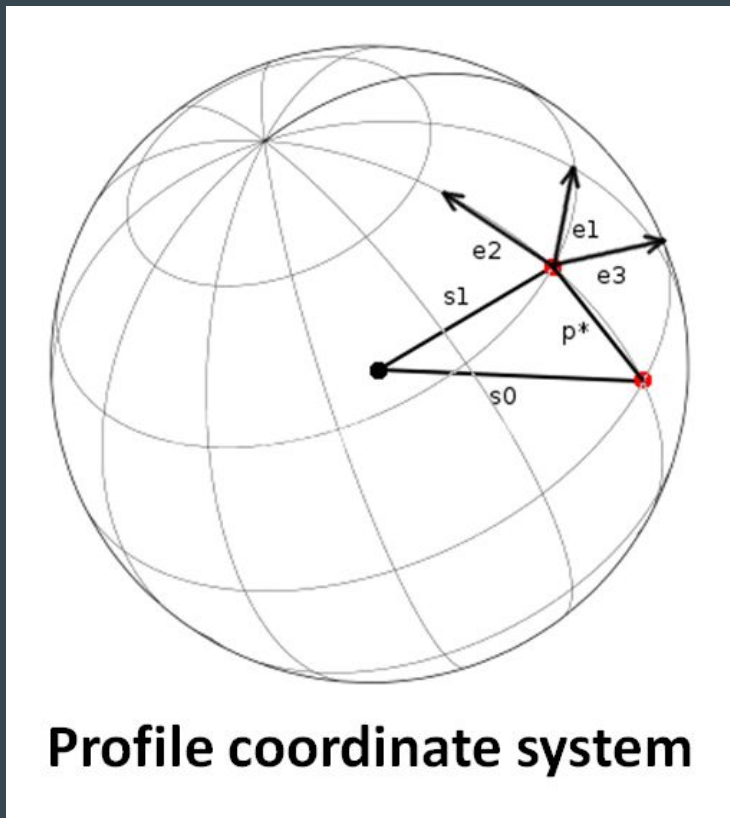


Build reference profiles across all images



Integrate the reflections and save output

Computing reflection shoeboxes



Use the kabsch model of a normal distribution on the surface of the Ewald sphere

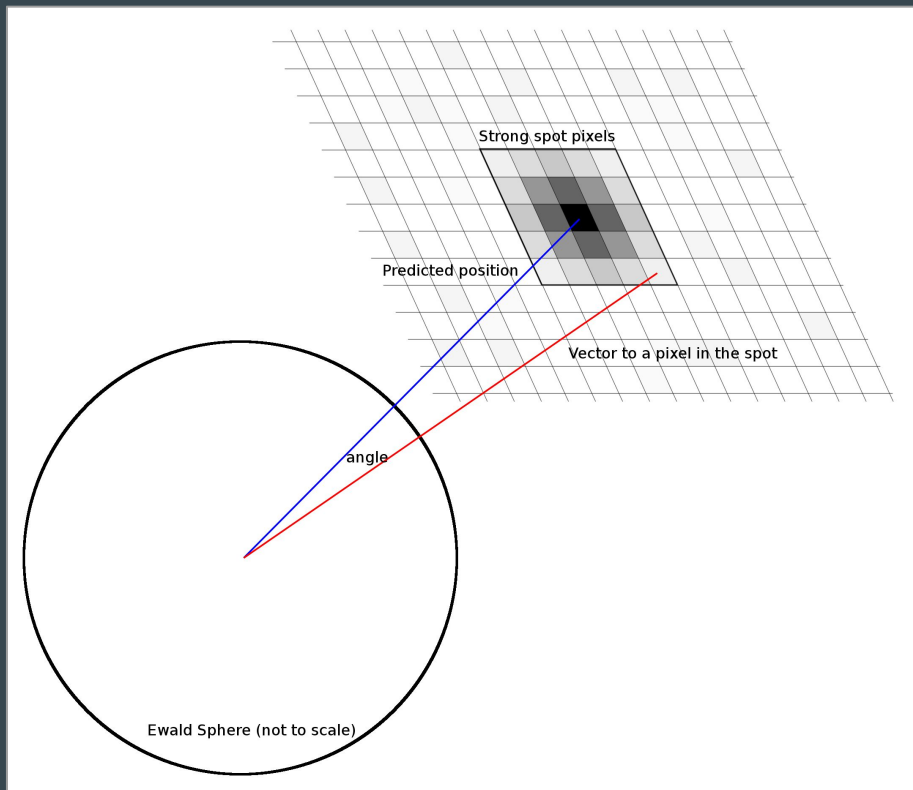
$$\exp\left(\frac{-\epsilon_1^2}{2\sigma_D^2}\right) \exp\left(\frac{-\epsilon_2^2}{2\sigma_D^2}\right) \exp\left(\frac{-\epsilon_3^2}{2\sigma_M^2}\right)$$

$$e_1 = \mathbf{S}_1 \times \mathbf{S}_0 / |\mathbf{S}_1 \times \mathbf{S}_0|$$

$$e_2 = \mathbf{S}_1 \times e_1 / |\mathbf{S}_1 \times e_1|$$

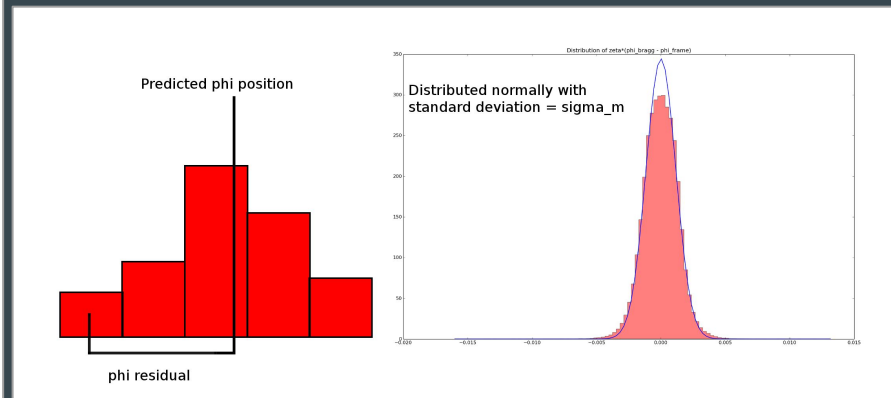
$$e_3 = (\mathbf{S}_1 + \mathbf{S}_0) / |\mathbf{S}_1 + \mathbf{S}_0|$$

Computing reflection shoeboxes

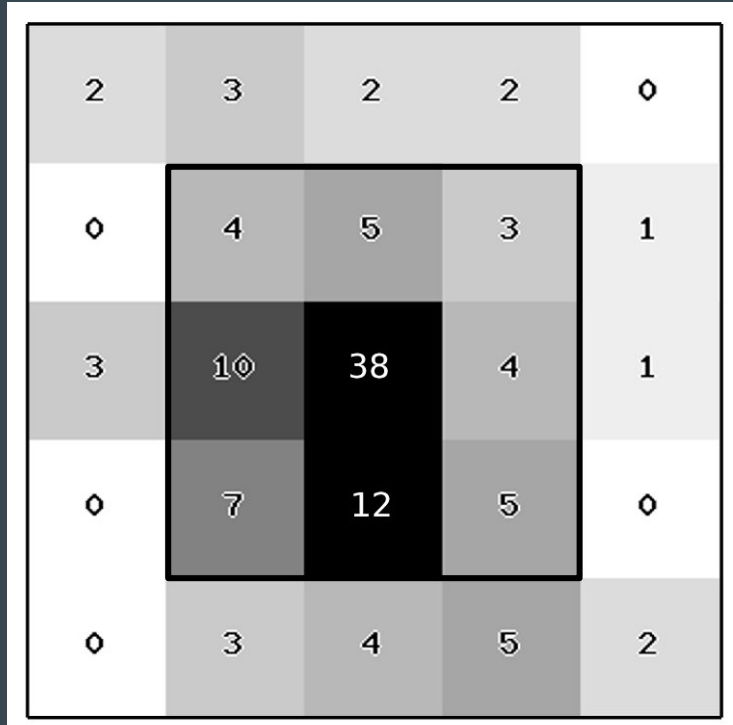


σ_D is calculated from the spread of angles between the predicted diffracted beam vector and the vector for each strong pixel in the spot

σ_M is calculated by maximum likelihood method assuming a normal distribution of phi residuals for each strong pixel in the spot



Integration



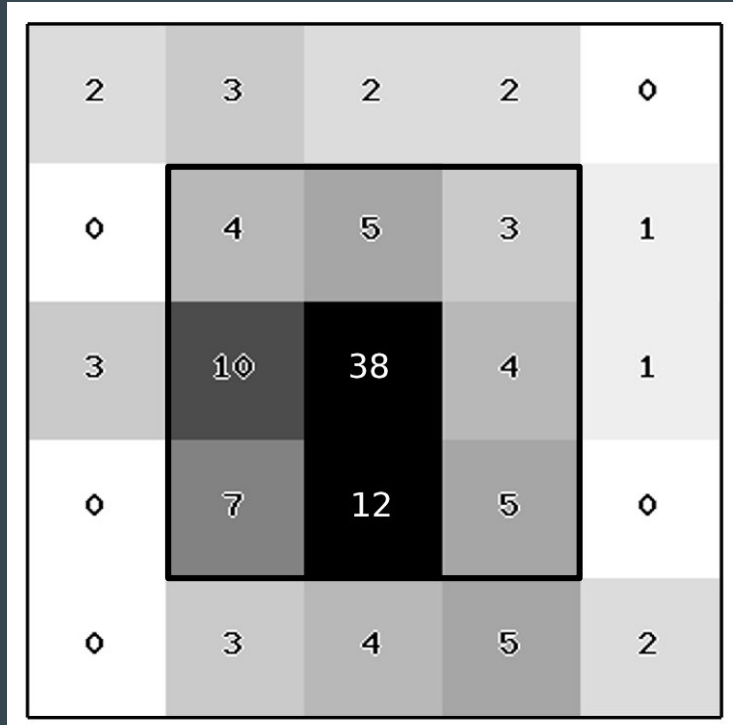
Summation integration: estimate the reflection intensity by summing the counts contributing to the reflection and subtracting the background

$$I = \text{SUM}(\text{Counts} - \text{Background})$$

Profile fitting: fit a known profile shape to the reflection to estimate the intensity

Need to estimate background under reflection peak

Background determination



Don't know background in signal region so estimate from the surrounding pixels

Background = MEAN(Background Counts)

Background = $(2+3+2+2+0+0+1+3+1+0+0+0+3+4+5+2) / 16$

Background = 2.5

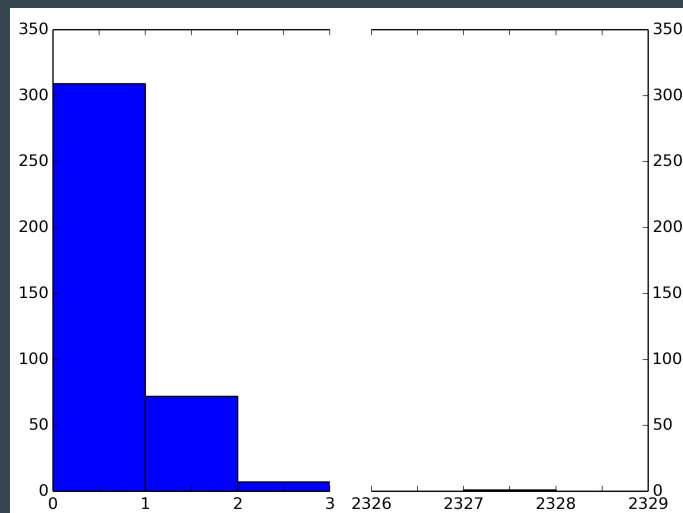
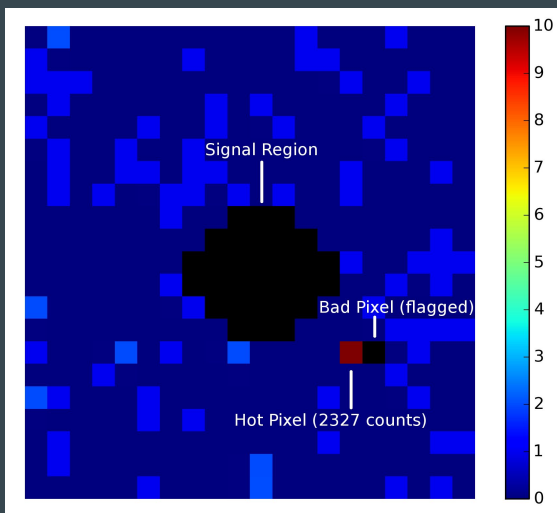
$I = \text{SUM}(\text{Counts} - \text{Background})$

$I = 4+5+3+10+38+4+7+12+5 - 9*2.5$

$I = 88 - 22.5$

$I = 65.5$

Background outlier pixels



	With Hot Pixel	Without Hot Pixel
<i>Mean</i>	6.20	0.22
<i>Variance/Mean</i>	2237.90	0.926

~1 for Poisson
distribution

Background modelling with outlier pixels

DIALS has multiple options for outlier pixel handling

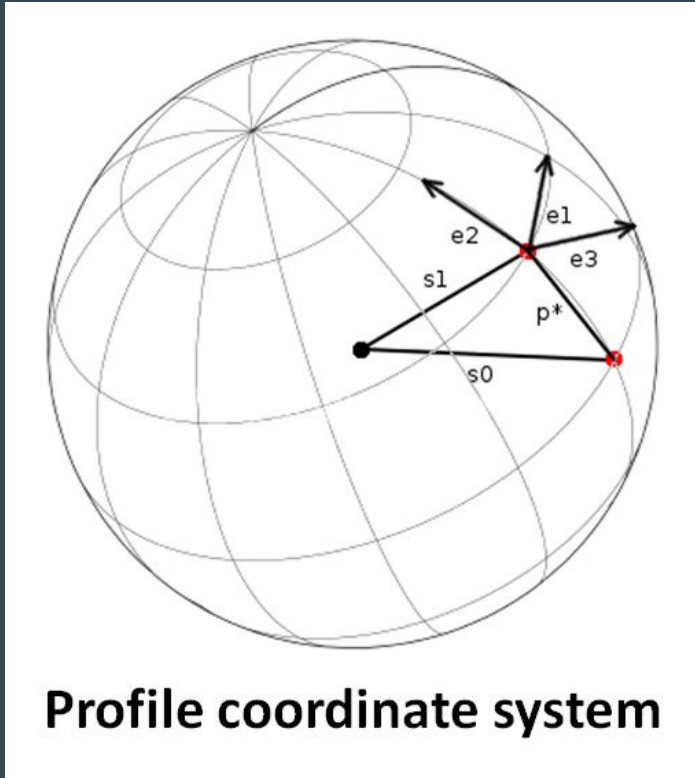
- Truncated - removed percentage of high and low valued pixels
- Normal - remove pixels above and below 3 STD around the mean
- Tukey - remove pixels based on interquartile range
- Plane - compute a plane and remove pixels based on deviation from plane (based on published mosflm algorithm)
- Normal - iteratively remove high valued pixels until they are approximately normally distributed (based on published XDS algorithm)

However, these methods assume a normal distribution and result in biases intensity estimates (particularly for low background)

Default algorithm in DIALS used a GLM algorithm

- assumes a Poisson distribution of pixel counts.
- Provides an unbiased estimate of the reflection background

3D profile fitting coordinate system



Use Kabsch coordinate system

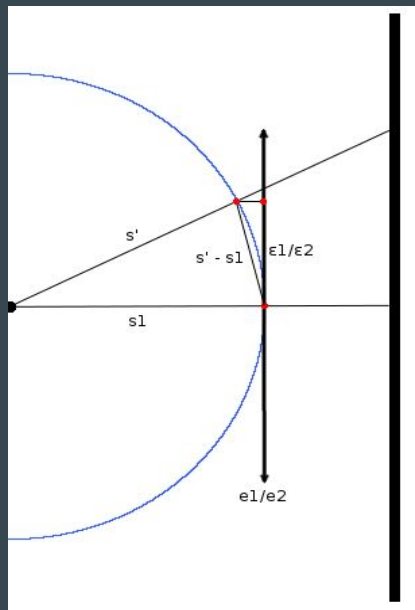
- Corrects for geometrical distortions
- Makes spots appear to have taken shortest path through Ewald sphere
- Model assumes a Gaussian profile in Kabsch coordinate system

$$e_1 = \mathbf{s}_1 \times \mathbf{s}_0 / |\mathbf{s}_1 \times \mathbf{s}_0|$$

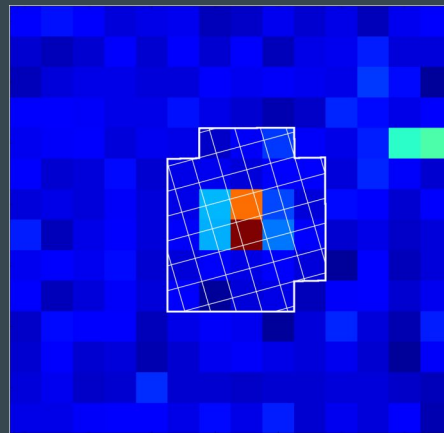
$$e_2 = \mathbf{s}_1 \times e_1 / |\mathbf{s}_1 \times e_1|$$

$$e_3 = (\mathbf{s}_1 + \mathbf{s}_0) / |\mathbf{s}_1 + \mathbf{s}_0|$$

3D profile fitting pixel gridding

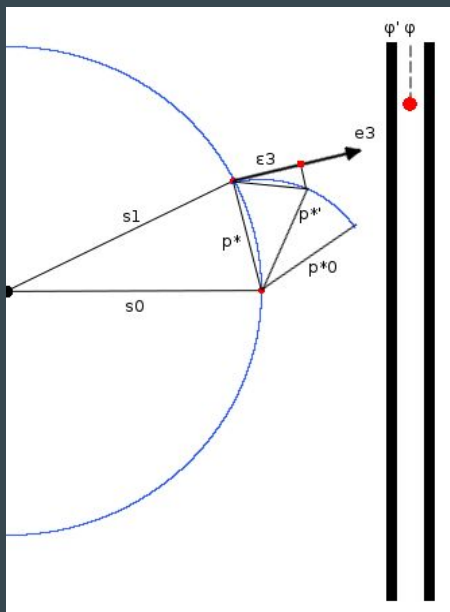


Pixels are mapped to the Ewald sphere

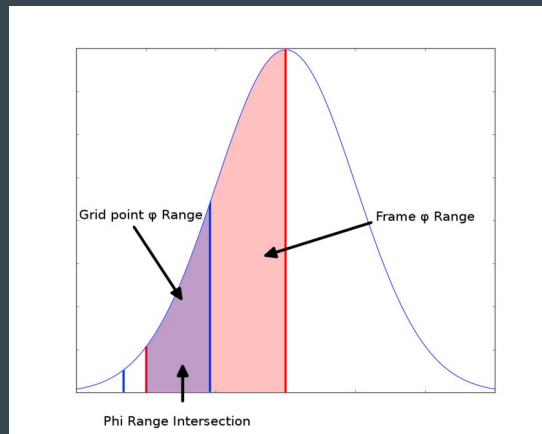


Counts are redistributed to Ewald sphere grid by computing fractional overlap of each pixel and Ewald sphere grid point

3D profile fitting phi gridding

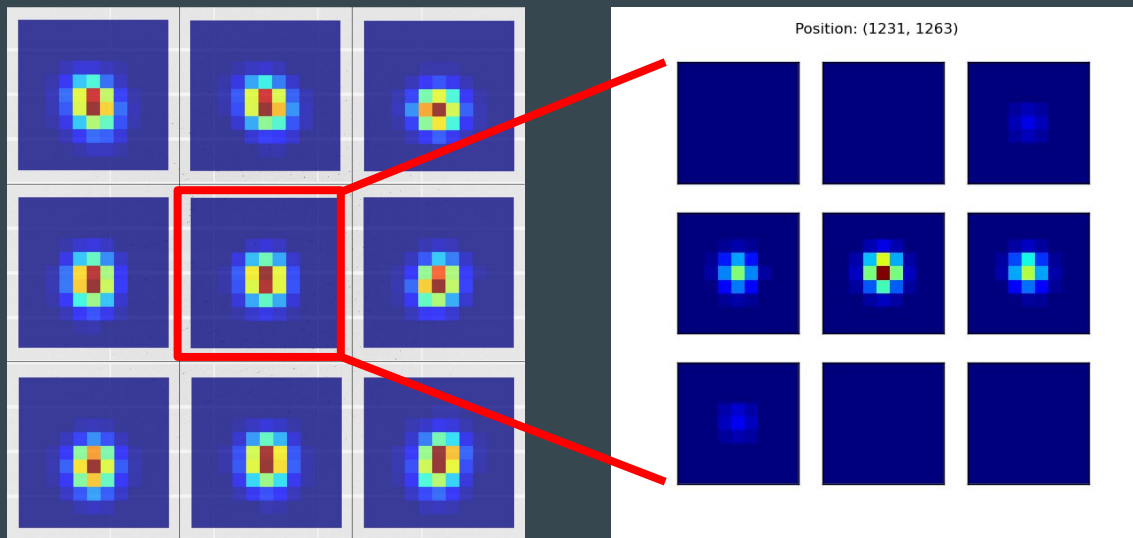


Frames are transformed to make reflection appear as if it took the shortest path through the Ewald sphere



Counts on each image are distributed by finding the angular overlap between each grid point and each image and integrating over the intersection

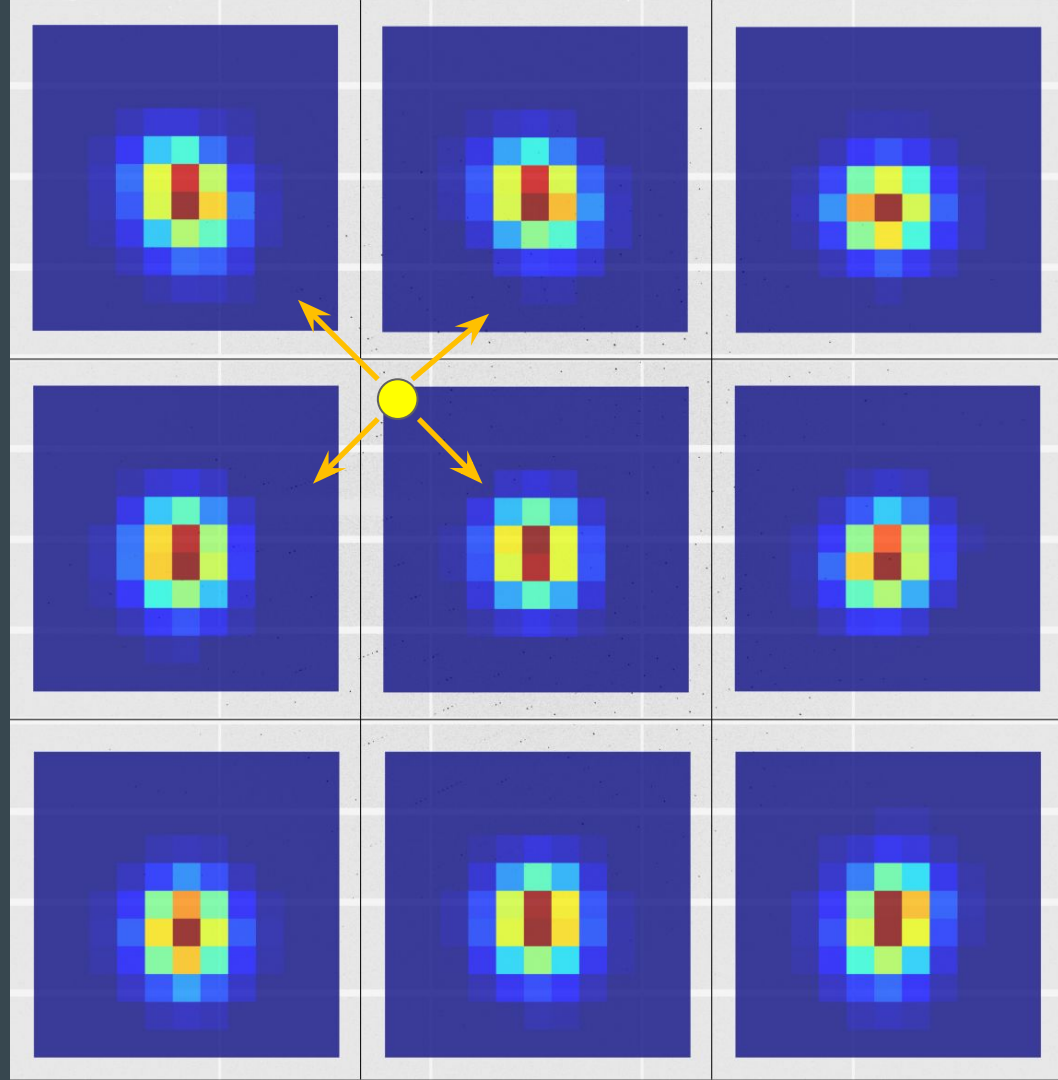
Building reference profiles



- Reference profiles are formed on a grid covering a given angular range
- Grid options include:
 - Rectangular grid (as in Mosflm)
 - Circular grid (as in XDS)
 - Projected Ewald sphere grid (needed for multi-panel detectors)
 - Single reflection

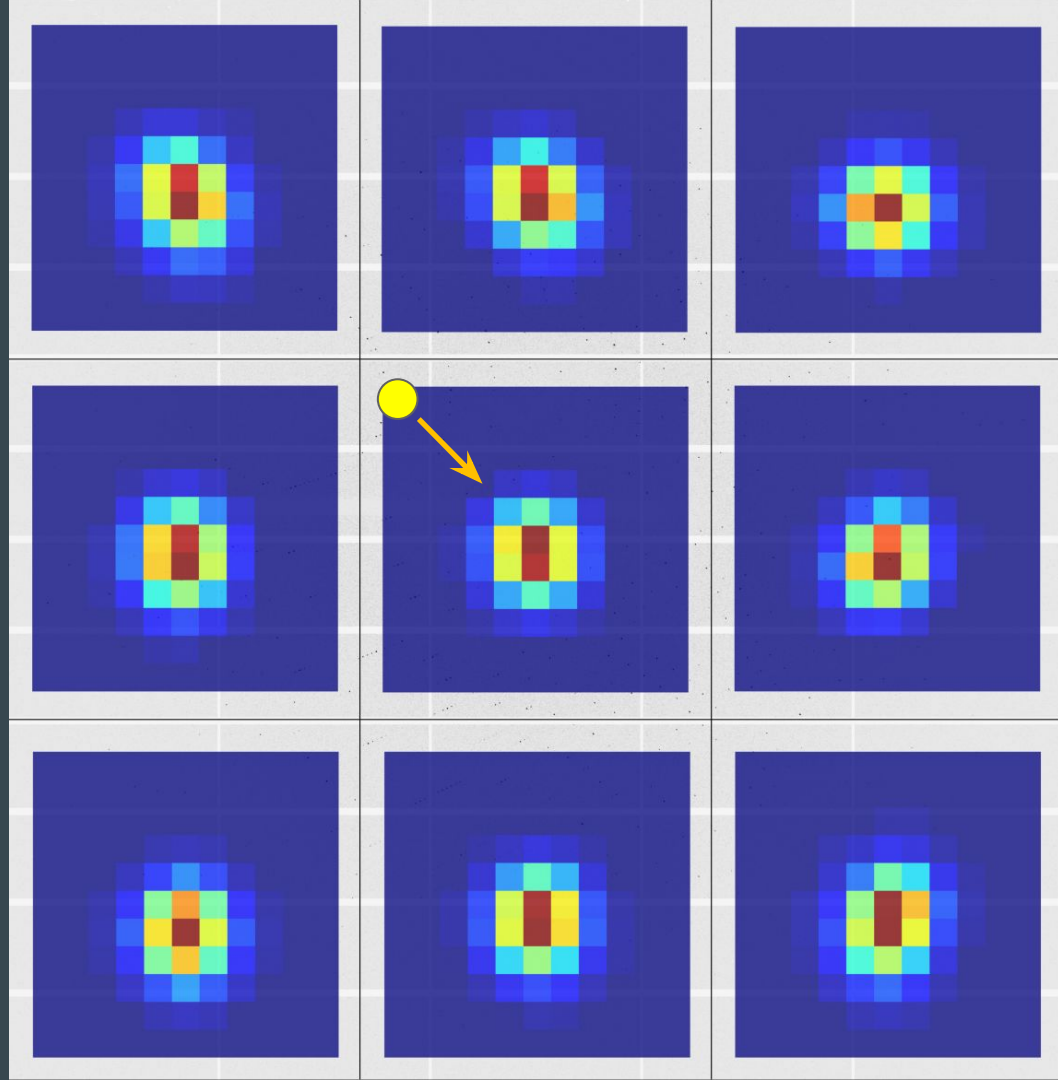
Building reference profiles

Each strong spot contributes to building the profile at adjacent grid points

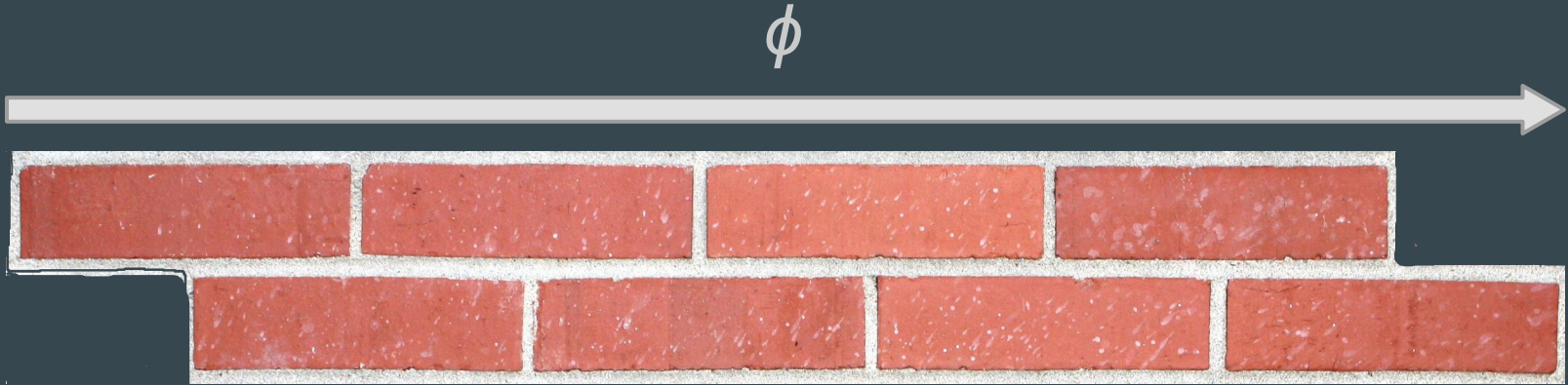


Fitting reference profiles

Each reflection is fitted against its closest reference profile



Fitting reference profiles



Profile for reflection at position x derived from average of strong reflections in block with centre nearest x

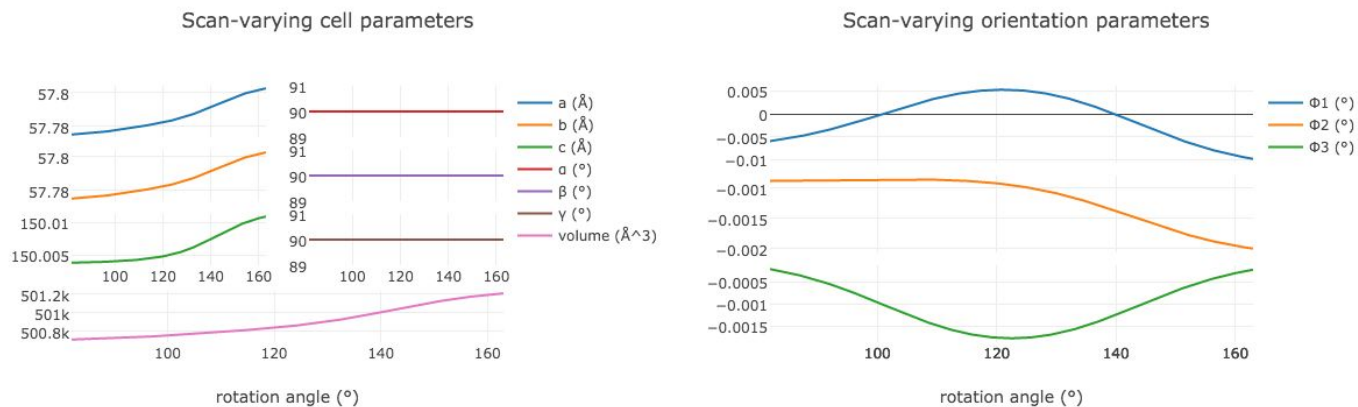
dials.report

Experiments

Crystal:	Space group:	P 4 (No. 75)	Unit cell:	(57.785 57.785 150.006 90.000 90.000 90.000)
U matrix:	$\begin{pmatrix} 0.3455 & -0.2590 & -0.9020 \\ 0.8913 & 0.3911 & 0.2292 \\ 0.2935 & -0.8831 & 0.3660 \end{pmatrix}$		B matrix:	$\begin{pmatrix} 0.0173 & 0.0000 & 0.0000 \\ -0.0000 & 0.0173 & 0.0000 \\ -0.0000 & 0.0000 & 0.0067 \end{pmatrix}$
A = UB:	$\begin{pmatrix} 0.0060 & -0.0045 & -0.0060 \\ 0.0154 & 0.0068 & 0.0015 \\ 0.0051 & -0.0153 & 0.0024 \end{pmatrix}$			
A sampled at 541 scan points			Average unit cell:	(57.786 57.786 150.006 90.000 90.000 90.000)

Experimental geometry

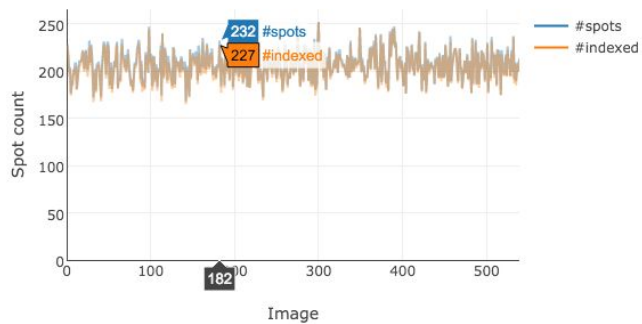
Analysis of scan-varying crystal model



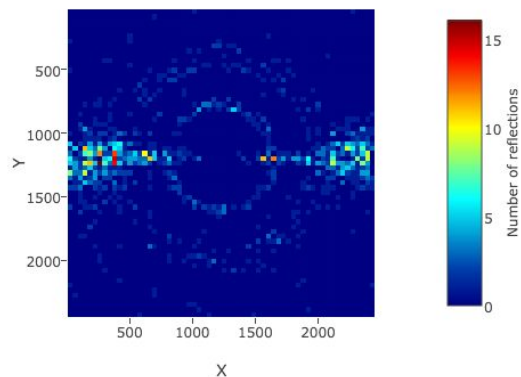
Analysis of strong reflections



Spot count per image

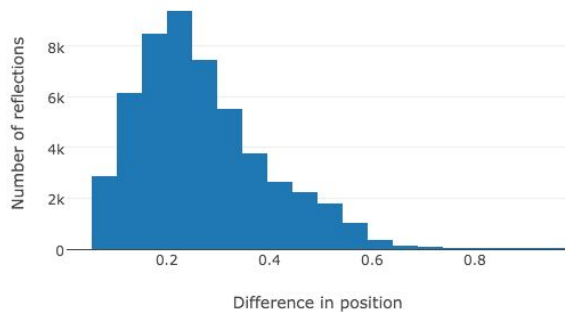


Number of unindexed reflections binned in X/Y

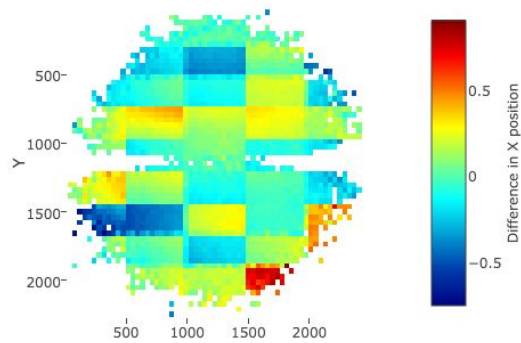


Analysis of reflection centroids

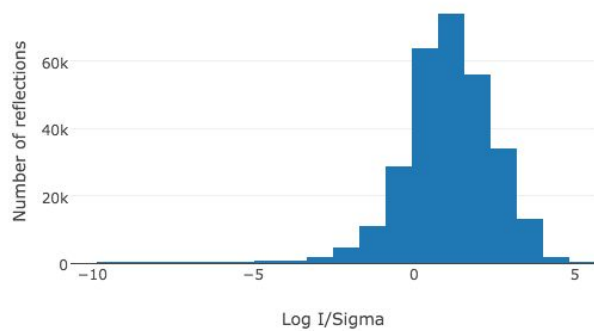
Difference between observed and calculated centroids



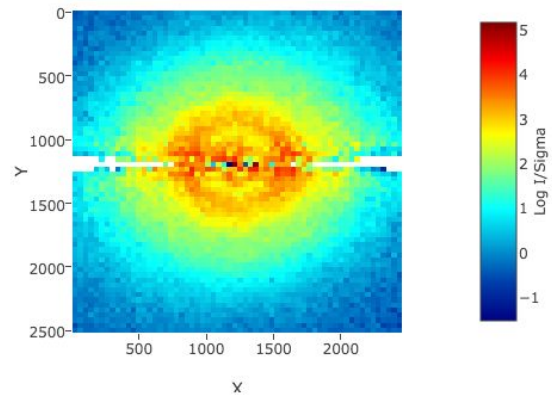
Difference between observed and calculated centroids in X



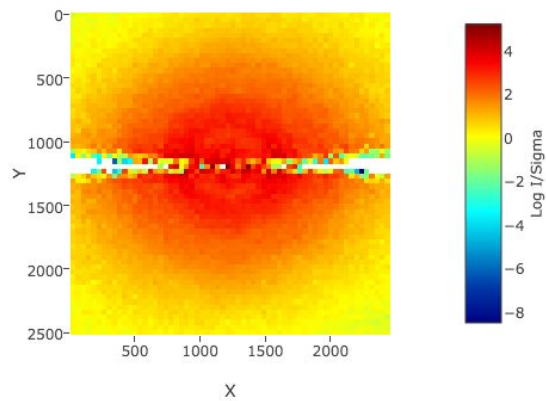
Log I/Sigma histogram



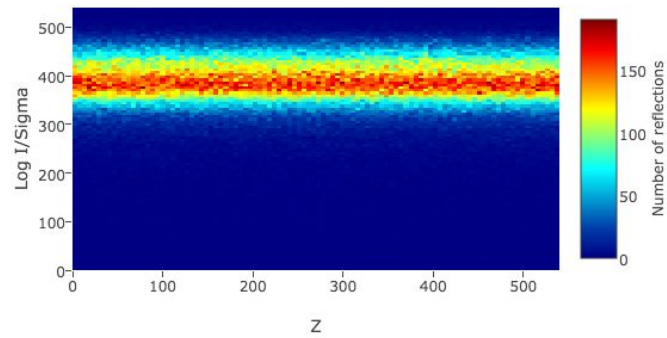
Distribution of $I(\text{sum})/\text{Sigma}$ vs X/Y



Distribution of $I(\text{prf})/\text{Sigma}$ vs X/Y



Distribution of I/Sigma vs Z



DIALS

Diffraction Integration for Advanced
Light Sources

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Processing in Detail

Introduction

DIALS processing may be performed by either running the individual tools (spot finding, indexing, refinement, integration, exporting to MTZ) or you can run `xia2 -dials`, which makes informed choices for you at each stage. In this tutorial we will run through each of the steps in turn, checking the output as we go. We will also enforce the correct lattice symmetry.

Tutorial data

The following example uses a Thaumatin dataset collected using beamline I04 at Diamond Light Source which is available for download from [DOI 10.5281/zenodo.10271](https://doi.org/10.5281/zenodo.10271)

Import

The first stage of step-by-step DIALS processing is to import the data - all that happens here is that the image headers are read, and a file describing their contents ([datablock.json](#)) is written. It's worth noting that if this file is changed subsequent processing can use this.

```
dials.import data/th_8_2_0*cbf
```

The output just describes what the software understands of the images it was passed, in this case one sweep of data containing 540 images.

The following parameters have been modified:

```
input {  
  datablock = <image files>  
}
```

```
-----  
DataBlock 0  
  format: <class 'dxtbx.format.FormatCBFMiniPilatusDLS6MSN100.FormatCBFMiniPilatusDLS6MSN100'>  
  num images: 540  
  num sweeps: 1  
  num stills: 0  
-----
```

Writing datablocks to datablock.json

Find Spots



Quick start guide

If you don't like reading manuals and just want to get started, try:

```
xia2 -2d /here/are/my/images
```

or:

```
xia2 -3d /here/are/my/images
```

or:

```
xia2 -dials /here/are/my/images
```

(remembering of course `-atom X` if you want anomalous pairs separating in scaling.) If this appears to do something sensible then you may well be home and dry. Some critical options:

Option	Usage
<code>-atom X</code>	tell xia2 to separate anomalous pairs i.e. $I(+)$ \neq $I(-)$ in scaling
<code>-2d</code>	tell xia2 to use MOSFLM and Aimless
<code>-3d</code>	tell xia2 to use XDS and XSCALE
<code>-3dii</code>	tell xia2 to use XDS and XSCALE , indexing with peaks found from all images
<code>-dials</code>	tell xia2 to use DIALS and Aimless

If this doesn't hit the spot, you'll need to read the rest of the documentation.

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Summary

- DIALS now used routinely for automated data processing via xia2
- XIA2 is the “friendly” DIALS user interface for synchrotron data, and is bundled with DIALS
- Software available from <http://dials.github.io/> under BSD license
- Binary releases available for Mac and Linux
- DIALS 1.3 is included in CCP4 7.0 (including Windows)
- GUI is currently in development

Acknowledgements

DIALS East

Gwyndaf Evans, Graeme Winter, David Waterman, James Parkhurst, Richard Gildea, Luis Fuentes-Montero, Markus Gerstel, Melanie Vollmar

DIALS West

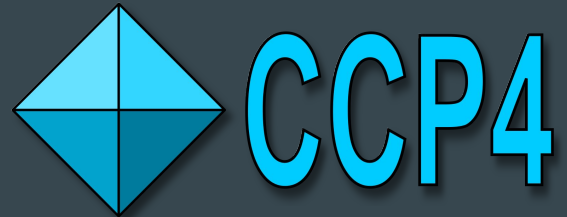
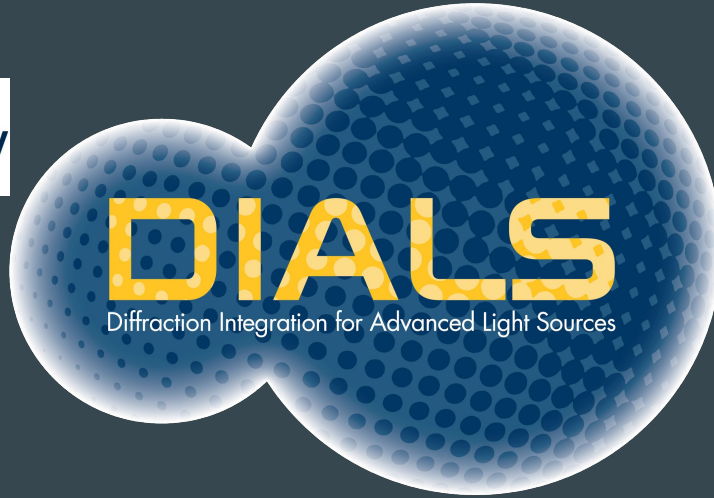
Nick Sauter, Aaron Brewster, Tara Michels-Clark, Iris Young

Lots of other people

Garib Murshudov, Andrew Leslie, Phil Evans, Harry Powell, Takanori Nakane

DIALS East-Diamond / CCP4





Thanks for listening!



<https://dials.diamond.ac.uk>

